



# Total Ionizing Dose Test Report

**No. 20T-RTAX2000S-CQ352-DGFPP1**

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August 31, 2020

## Table of Contents

<b>I. Summary Table .....</b>	<b>3</b>
<b>II. Total Ionizing Dose (TID) Testing .....</b>	<b>3</b>
A. Device-Under-Test (DUT) and Irradiation Parameters .....	3
B. Test Method .....	4
C. Design and Parametric Measurements .....	5
<b>III. Test Results .....</b>	<b>6</b>
A. Functionality.....	6
B. Power Supply Current (ICCA and ICCI) .....	6
C. Single-Ended Input Logic Threshold (VIL/VIH) .....	10
D. Differential Input (LVPECL) Threshold Voltage (VIL/VIH) .....	11
E. Output-Drive Voltage (VOL/VOH).....	12
F. Propagation Delay.....	13
G. Transition Characteristics .....	15
<b>Appendix A: DUT Bias .....</b>	<b>27</b>
<b>Appendix B: DUT Design Schematics and Verilog Files .....</b>	<b>29</b>

**TOTAL IONIZING DOSE TEST REPORT**
*No. 20T-RTAX2000S-CQ352-DGFPP1*
*July 31, 2020*

## I. Summary Table

Parameter	Tolerance
1. Gross Functionality	Passed 300 krad (SiO <sub>2</sub> )
2. Power Supply Current (ICCA/ICCI)	Passed 300 krad (SiO <sub>2</sub> )
3. Input Threshold (VTIL/VIH)	Passed 300 krad (SiO <sub>2</sub> )
4. Output Drive (VOL/VOH)	Passed 300 krad (SiO <sub>2</sub> )
5. Propagation Delay	Passed 300 krad (SiO <sub>2</sub> ) for 10% degradation criterion
6. Transition Characteristics	Passed 300 krad (SiO <sub>2</sub> )

## II. Total Ionizing Dose (TID) Testing

This testing is designed on the base of an extensive database (see TID data of antifuse-based FPGAs at <http://www.klabs.org> and <http://www.microsemi.com/soc>) accumulated from the TID testing of many generations of antifuse-based FPGAs.

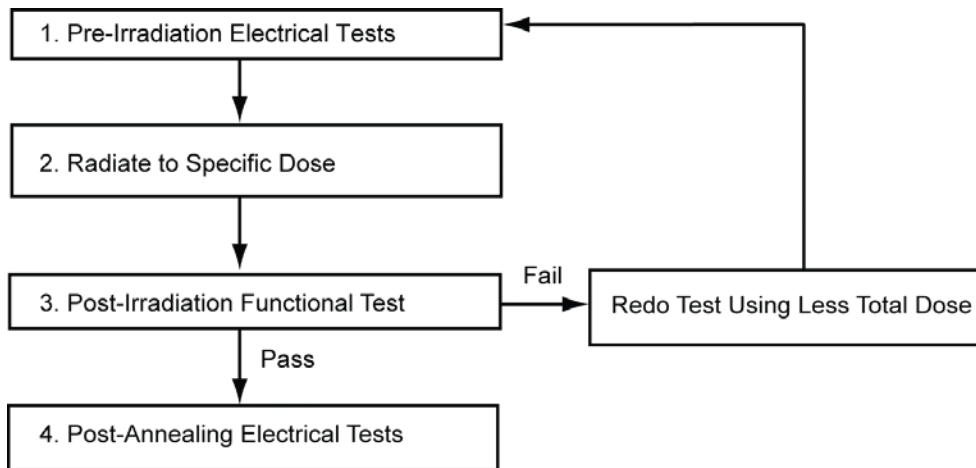
### A. Device-Under-Test (DUT) and Irradiation Parameters

Table 1 lists the DUT and irradiation parameters. During irradiation, each input and most of the output is grounded through a 1 M $\Omega$  resistor; during annealing, each input or output is tied to the ground or VCCI with a 2.7 k $\Omega$  resistor. Appendix A contains the schematics of the irradiation-bias circuit.

**Table 1 DUT and Irradiation Parameters**

Part Number	RTAX2000S
Package	CQ352
Foundry	United Microelectronics Corp.
Technology	0.15 $\mu$ m CMOS
DUT Design	TOP_AX2000S_TID
Die Lot Number	DGFPP1
Quantity Tested	6
Serial Number	300 krad(SiO <sub>2</sub> ): 14004, 14015 200 krad(SiO <sub>2</sub> ): 13992, 13993 100 krad(SiO <sub>2</sub> ): 13964, 13974
Radiation Facility	Defense Microelectronics Activity
Radiation Source	Co-60
Dose Rate ( $\pm$ 5%)	10 krad(SiO <sub>2</sub> )/min
Irradiation Temperature	Room
Irradiation and Measurement Bias (VCCI/VCCA)	Static at 3.3 V/1.5 V

## B. Test Method



**Figure 1 Parametric Test Flow Chart**

The test method generally follows the guidelines in the military standard TM1019.8. Figure 1 is the flow chart describing the steps for functional and parametric tests, irradiation, and post-irradiation annealing.

The accelerated aging, or rebound test mentioned in TM1019.8, is unnecessary; because there is no adverse time-dependent effect (TDE) in Microsemi products manufactured by deep sub-micron CMOS technologies. Elevated temperature annealing basically reduces the effects originating from radiation-induced leakage currents. As indicated by test data in the following sections, the predominant radiation effects in RTAX2000S are due to radiation-induced leakage currents.

Room temperature annealing is performed in this test; the duration is approximately 7 days.

### C. Design and Parametric Measurements

The DUT uses a high utilization, generic design (TOP\_AX2000S\_TID) to evaluate total dose effects for typical space applications. Appendix B contains the schematics and Verilog files of this design.

Table 2 lists measured electrical parameters and the corresponding logic design. The functionality is measured on the output pin (O\_BS) of a combinational buffer-string with 14,000 buffers, output pins (O\_ANDP\_CLKF, O\_ORP\_CLKF, O\_FF\_CLKF, O\_ANDC\_CLKF, O\_ORC\_CLKF, O\_ANDP\_CLKG, O\_ORP\_CLKG, O\_FF\_CLKG, O\_ANDC\_CLKG, O\_ORC\_CLKG, O\_ANDP\_CLKH, O\_ORP\_CLKH, O\_FF\_CLKH, O\_ANDC\_CLKH, O\_ORC\_CLKH, O\_ANDP\_HCLKA, O\_ORP\_HCLKA, O\_FF\_HCLKA, O\_ANDC\_HCLKA, and O\_ORC\_HCLKA) of four (4) shift registers with 10,728 bits total, and half of the output pins (OUTX0, OUTX1, OUTX2, OUTX3, OUTX4, OUTX5, OUTX6 and OUTX7) of the embedded RAM configured as 16K×16.

ICC is measured on the power supply of the logic-array (ICCA) and I/O (ICCI) respectively. The input logic threshold (VIL/VIH) is measured on single-ended inputs EN8, DA, IO\_11, IO\_12, IO\_13, IO\_14, IO\_15 and IO\_16, and also on differential inputs DIO\_11P, DIO\_12P, DIO\_13P, DIO\_14P, DIO\_15P, DIO\_16P and DIO\_17P. The differential inputs are configured as LVPECL instead of LVDS; because LVPECL using 3.3 VDC, is worse than LVDS which uses 2.5 VDC. During the measurement on the differential inputs, the N (negative) side of the differential pair is biased at 1.8 V. The output-drive voltage (VOL/VOH) is measured on QA0 and YQ0. The propagation delay is measured on the output (O\_BS) of the buffer string; the definition is the time delay from the triggering edge at the CLOCK input to the switching edge at the output O\_BS. Both the delays of low-to-high and high-to-low output transitions are measured; the reported delay is the average of these two measurements. The transition characteristics, measured on the output O\_BS, are shown as oscilloscope captures.

**Table 2 Logic Design for Parametric Measurements**

Parameters	Logic Design
1. Functionality	All key logic functions (O_BS, O_ANDP_CLKF, O_ORP_CLKF, O_FF_CLKF, O_ANDC_CLKF, O_ORC_CLKF, O_ANDP_CLKG, O_ORP_CLKG, O_FF_CLKG, O_ANDC_CLKG, O_ORC_CLKG, O_ANDP_CLKH, O_ORP_CLKH, O_FF_CLKH, O_ANDC_CLKH, O_ORC_CLKH, O_ANDP_HCLKA, O_ORP_HCLKA, O_FF_HCLKA, O_ANDC_HCLKA, and O_ORC_HCLKA), and outputs of embedded RAM (OUTX0, OUTX1, OUTX2, OUTX3, OUTX4, OUTX5, OUTX6 and OUTX7)
2. ICC (ICCA/ICCI)	DUT power supply
3. Input Threshold (VIL/VIH)	Single ended inputs (EN8/YQ0, DA/QA0, IO_11/IO_01, IO_12/IO_02, IO_13/IO_03, IO_14/IO_04, IO_15/IO_05, IO_16/IO_06), and differential inputs (DIO_11P/DIO_01, DIO_12P/DIO_02, DIO_13P/DIO_03, DIO_14P/DIO_04, DIO_15P/DIO_05, DIO_16P/DIO_06, DIO_17P/DIO_07)
4. Output Drive (VOL/VOH)	Output buffer (EN8/YQ0, DA/QA0)
5. Propagation Delay	String of buffers (CLOCK to O_BS)
6. Transition Characteristic	String of buffers output (O_BS)

### III. Test Results

#### A. Functionality

Every DUT passed the pre-irradiation and post-annealing functional tests. The as-irradiated DUT is functionally tested on the output (O\_FF\_HCLKA) of the largest shift register.

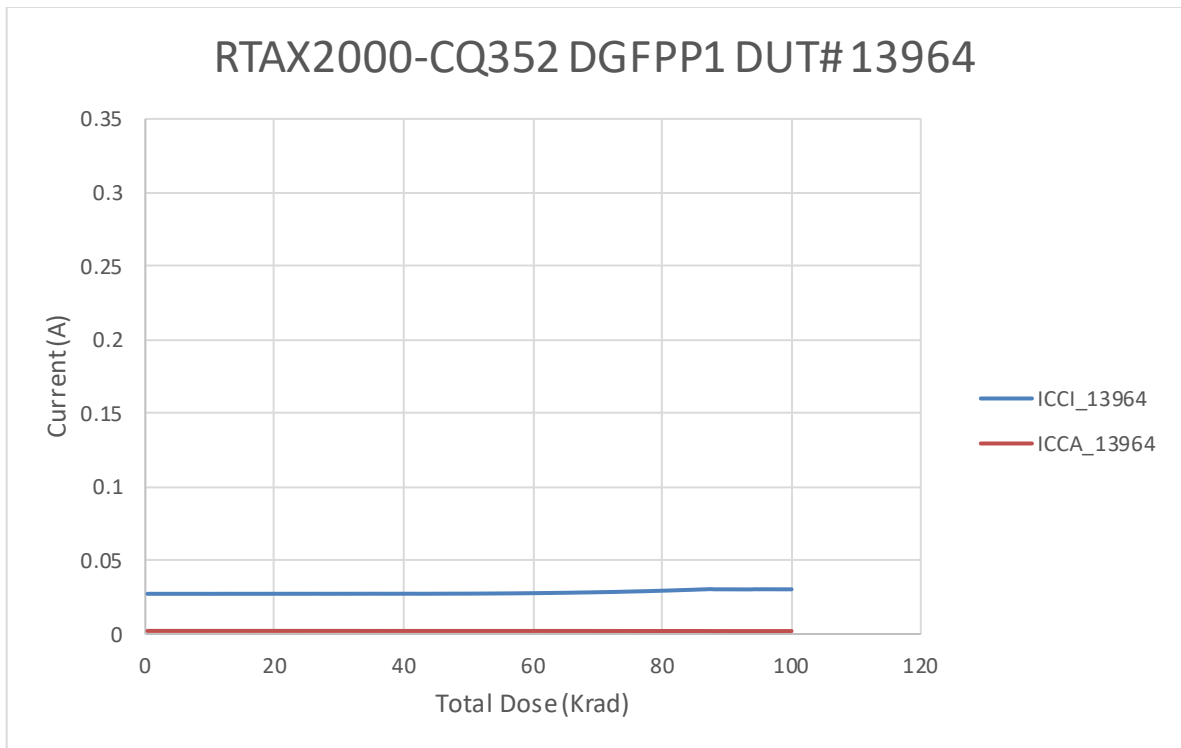
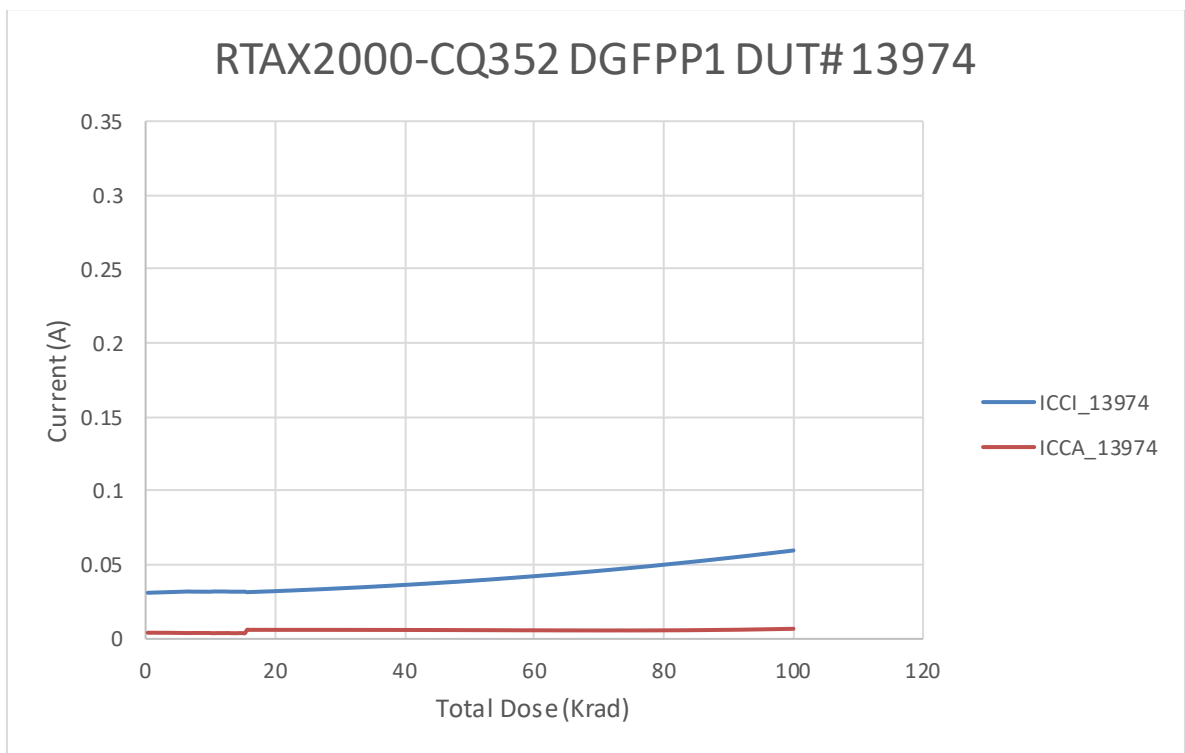
#### B. Power Supply Current (ICCA and ICCI)

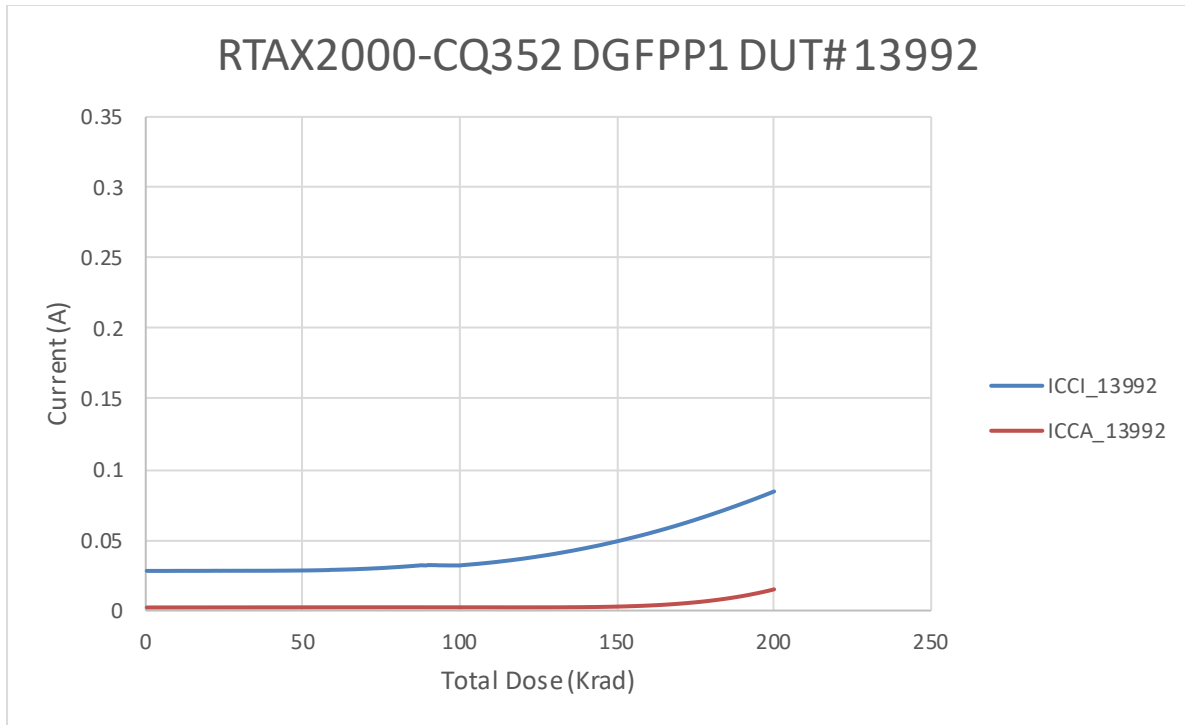
Figure 2 through Figure 7 plot the influx standby ICCA and ICCI versus total dose for each DUT. The post-annealing ICC for four different bit patterns, all '0', all '1', checkerboard and inverted-checkerboard, in the RAM are basically the same.

Table 3 summarizes the pre-irradiation, post-irradiation right after irradiation and before anneal, and post-annealing ICCA and ICCI data.

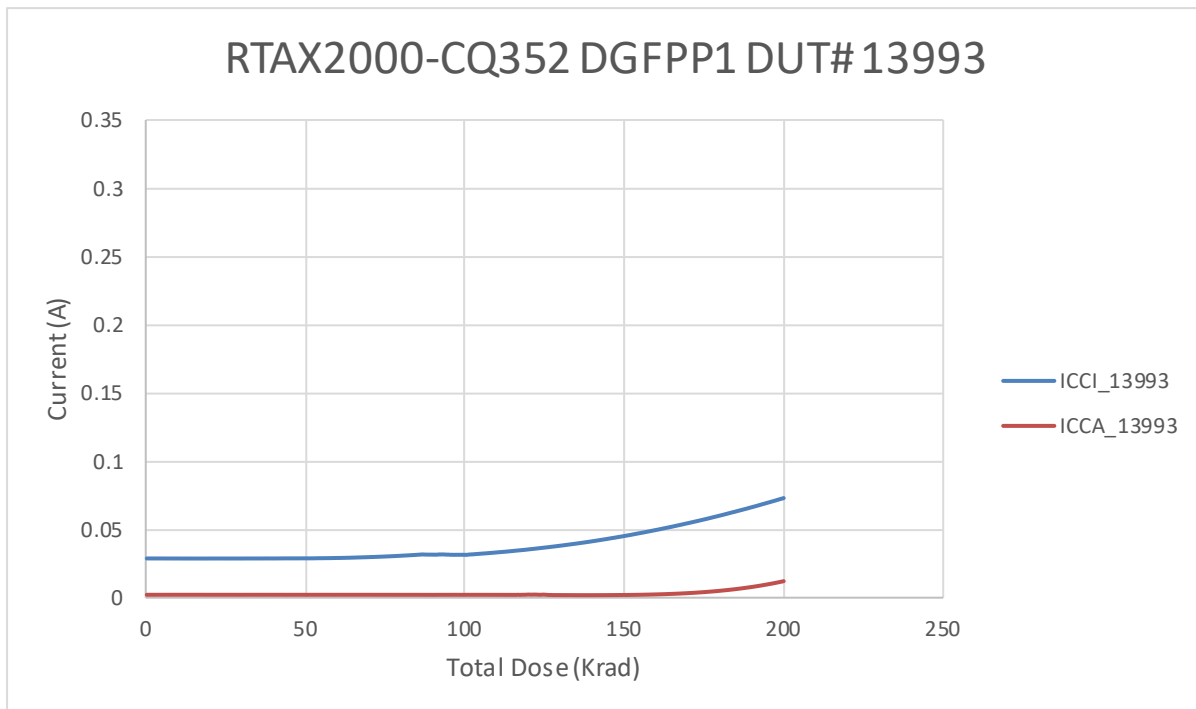
**Table 3 Pre-Irradiation, Post Irradiation and Post-Annealing ICC**

DUT	Total Dose	ICCA (mA)			ICCI (mA)		
		Pre-irrad	Post-irrad	Post-ann	Pre-irrad	Post-irrad	Post-ann
13964	100 krad	2.1	1.9	1.8	26.9	20.0	28.1
13974	100 krad	4.0	3.7	3.4	28.8	31.7	29.8
13992	200 krad	2.1	13.5	2.4	27.8	81.4	46.2
13993	200 krad	2.0	11.0	2.0	28.4	70.1	41.3
14004	300 krad	3.2	168	17.5	27.8	173	69.8
14015	300 krad	4.5	267	40.1	28.4	141	58.2


**Figure 2 DUT 13964 Influx ICCA and ICCI**

**Figure 3 DUT 13974 Influx ICCA and ICCI**

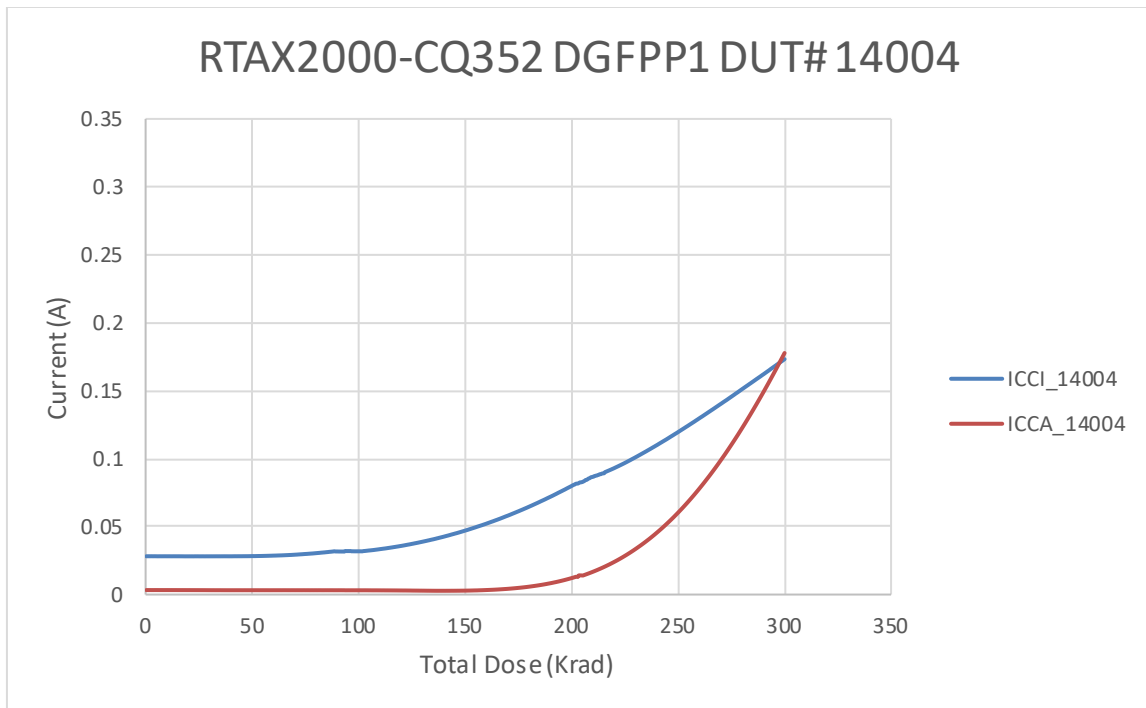
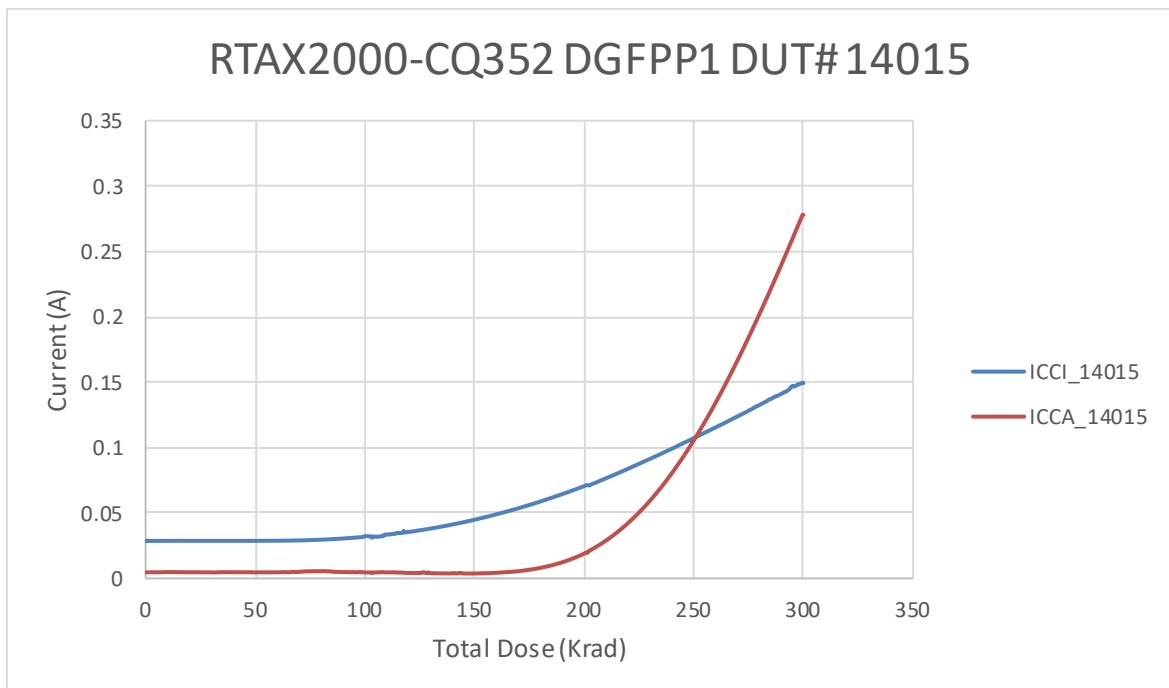


**Figure 4 DUT 13992 Influx ICCA and ICCI**



**Figure 5 DUT 13993 Influx ICCA and ICCI**




**Figure 6 DUT 14004 Influx ICCA and ICCI**

**Figure 7 DUT 14015 Influx ICCA and ICCI**

### C. Single-Ended Input Logic Threshold (VIL/VIH)

Table 4a through Table 4c list the pre-irradiation and post-annealing single-ended input logic thresholds. All data are within the specification limits. The post-annealing shift in every case is very small.

Table 4a Pre-Irradiation and Post-Annealing Input Thresholds

DUT	14004 (300 krad)				14015 (300 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DA	1420	1390	1415	1400	1415	1415	1395	1390
EN8	1385	1390	1380	1400	1405	1385	1400	1390
IO_I_6	1400	1385	1395	1400	1410	1390	1395	1395
IO_I_5	1390	1405	1380	1410	1405	1380	1410	1400
IO_I_4	1390	1400	1390	1410	1415	1395	1405	1395
IO_I_3	1335	1410	1355	1435	1370	1350	1430	1420
IO_I_2	1395	1410	1390	1420	1395	1390	1420	1410
IO_I_1	1390	1405	1385	1415	1395	1385	1415	1405

Table 4b Pre-Irradiation and Post-Annealing Input Thresholds

DUT	13992 (200 krad)				13993 (200 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DA	1420	1420	1400	1390	1420	1420	1395	1385
EN8	1390	1380	1400	1390	1395	1395	1395	1390
IO_I_6	1400	1395	1400	1385	1410	1410	1400	1395
IO_I_5	1390	1380	1410	1400	1415	1400	1405	1395
IO_I_4	1395	1390	1405	1390	1395	1395	1405	1390
IO_I_3	1355	1355	1435	1425	1350	1355	1430	1420
IO_I_2	1395	1395	1425	1410	1390	1385	1415	1405
IO_I_1	1395	1385	1410	1405	1390	1390	1415	1405

Table 4c Pre-Irradiation and Post-Annealing Input Thresholds

DUT	13964 (100 krad)				13974 (100 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DA	1425	1420	1405	1395	1420	1420	1395	1395
EN8	1395	1390	1405	1390	1385	1380	1395	1395
IO_I_6	1405	1400	1400	1400	1400	1395	1400	1395
IO_I_5	1395	1390	1415	1390	1390	1380	1410	1400
IO_I_4	1405	1395	1405	1395	1395	1395	1400	1390
IO_I_3	1370	1365	1440	1365	1350	1355	1430	1420
IO_I_2	1400	1395	1425	1395	1390	1390	1415	1405
IO_I_1	1400	1395	1415	1395	1385	1385	1410	1405

## D. Differential Input (LVPECL) Threshold Voltage (VIL/VIH)

Table 5a through Table 5c list the LVPECL differential input threshold voltage changes due to irradiations. All pins show negligible changes, and all the data are within the specification.

**Table 5a Pre-Irradiation and Post-Annealing Differential Input Thresholds**

DUT	14004 (300 krad)				14015 (300 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DIO_IP_1	1795	1795	1790	1790	1795	1795	1790	1790
DIO_IP_2	1780	1780	1785	1780	1790	1790	1790	1790
DIO_IP_3	1790	1790	1785	1785	1795	1795	1790	1790
DIO_IP_4	1790	1790	1800	1795	1780	1785	1790	1785
DIO_IP_5	1795	1795	1795	1795	1795	1795	1790	1790
DIO_IP_6	1790	1785	1790	1790	1790	1790	1795	1795
DIO_IP_7	1790	1790	1785	1785	1790	1790	1785	1785
DELETE	1370	1365	1390	1385	1375	1370	1390	1385

**Table 5b Pre-Irradiation and Post-Annealing Differential Input Thresholds**

DUT	13992 (200 krad)				13993 (200 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DIO_IP_1	1790	1790	1785	1785	1790	1790	1785	1785
DIO_IP_2	1790	1790	1795	1795	1790	1795	1795	1795
DIO_IP_3	1790	1790	1790	1785	1800	1800	1795	1795
DIO_IP_4	1790	1780	1790	1790	1785	1780	1790	1790
DIO_IP_5	1795	1795	1790	1790	1790	1790	1785	1785
DIO_IP_6	1780	1785	1790	1790	1785	1785	1790	1790
DIO_IP_7	1790	1790	1790	1790	1795	1795	1790	1790
DELETE	1370	1365	1395	1385	1375	1370	1395	1390

**Table 5c Pre-Irradiation and Post-Annealing Differential Input Thresholds**

DUT	13964 (100 krad)				13974 (100 krad)			
	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann	Pre-Irrad	Post-Ann
	VIL (mV)		VIH (mV)		VIL (mV)		VIH (mV)	
DIO_IP_1	1795	1795	1790	1790	1795	1795	1790	1790
DIO_IP_2	1785	1785	1790	1790	1790	1790	1795	1790
DIO_IP_3	1790	1790	1785	1785	1800	1800	1795	1790
DIO_IP_4	1785	1785	1790	1790	1785	1785	1795	1795
DIO_IP_5	1795	1790	1790	1790	1795	1795	1795	1790
DIO_IP_6	1785	1785	1790	1790	1780	1780	1790	1790
DIO_IP_7	1795	1795	1790	1790	1795	1795	1795	1795
DELETE	1375	1375	1395	1390	1370	1365	1385	1385

### E. Output-Drive Voltage (VOL/VOH)

The pre-irradiation and post-annealing VOL/VOH are listed in Tables 6 and 7. The post-annealing data are within the specification limits.

**Table 6 Pre-Irradiation and Post-Annealing VOL (mV) at Various Sinking Current**

Sourcing Current	Pin\DUT	14004 (300 krad)		14015 (300 krad)		13992 (200 krad)		13993 (200 krad)		13964 (100 krad)		13974 (100 krad)	
		Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an
1 mA	QA0	7	7	7	7	7	7	7	7	8	7	7	7
	YQ0	9	9	8	9	9	9	8	8	8	8	8	9
12 mA	QA0	89	86	89	85	90	86	89	86	90	87	89	86
	YQ0	97	96	95	94	98	96	96	95	96	95	96	96
20 mA	QA0	150	144	148	142	150	144	149	144	150	145	148	144
	YQ0	162	160	159	157	163	160	160	159	160	159	159	159
50 mA	QA0	382	366	377	362	383	366	382	366	383	371	378	368
	YQ0	413	407	404	399	415	408	407	403	406	405	406	405
100 mA	QA0	814	779	804	769	816	780	814	779	819	791	807	783
	YQ0	877	860	857	842	883	863	864	852	862	858	863	859

**Table 7 Pre-Irradiation and Post-Annealing VOH (mV) at Various Sourcing Current**

Sourcing Current	Pin\DUT	14004 (300 krad)		14015 (300 krad)		13992 (200 krad)		13993 (200 krad)		13964 (100 krad)		13974 (100 krad)	
		Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an	Pre-rad	Post-an
1 mA	QA0	3290	3286	3290	3286	3290	3287	3290	3287	3290	3288	3290	3288
	YQ0	3288	3285	3288	3286	3288	3287	3288	3287	3288	3289	3288	3289
8 mA	QA0	3225	3220	3225	3220	3225	3222	3225	3221	3225	3223	3225	3224
	YQ0	3217	3216	3220	3217	3219	3217	3219	3218	3220	3220	3220	3220
20 mA	QA0	3112	3108	3113	3108	3112	3109	3111	3108	3111	3110	3112	3111
	YQ0	3103	3094	3102	3096	3100	3096	3100	3096	3102	3100	3101	3099
50 mA	QA0	2816	2810	2817	2811	2816	2813	2811	2808	2813	2813	2814	2814
	YQ0	2789	2776	2792	2779	2786	2777	2787	2778	2793	2786	2790	2783
100 mA	QA0	2241	2230	2243	2234	2240	2235	2226	2223	2234	2233	2236	2236
	YQ0	2189	2161	2199	2172	2183	2161	2186	2166	2200	2182	2192	2174

## F. Propagation Delay

The propagation delay was measured in-situ, post-irradiation, and post-annealing. The results are plotted in Figure 8, and listed in Table 8. As shown in Figure 8, the propagation delay moves with the total dose, but the change is small throughout the irradiation. Referring to influx static current plots (Figure 2 through Figure 7), a device probably heats up as the dose increases. The rising temperature could be the root cause of the increasing trend at high doses. The post-annealing data, on the other hand, show decreased delay in every case.

The radiation delta in every case is well within the 10% degradation criterion. The user can take the worst case for the design margin consideration.

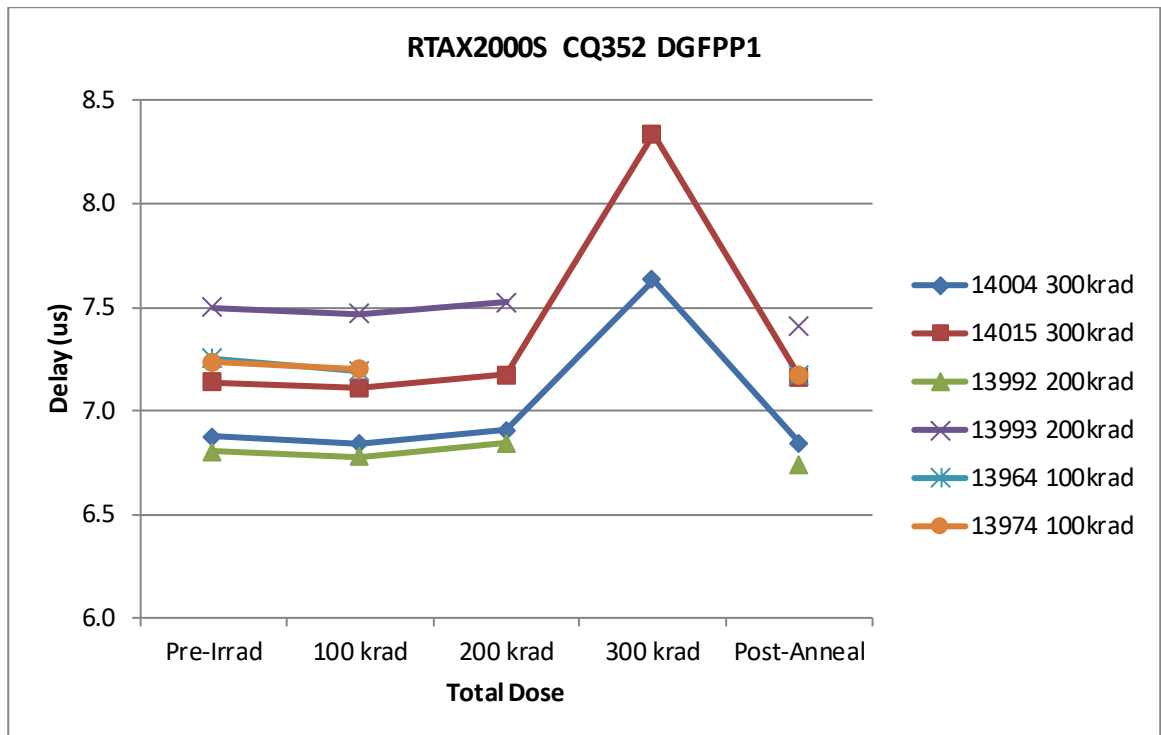


Figure 8 In-Situ Propagation Delay versus Total Dose

**Table 8 Radiation-Induced Propagation Delay Degradations**

Delay ( $\mu$ s)							
	DUT	Total Dose	Pre-rad	100 krad	200 krad	300 krad	Post-ann
	14004	300 krad	6.875	6.84	6.905	7.63	6.845
	14015	300 krad	7.135	7.11	7.175	8.335	7.165
	13992	200 krad	6.805	6.775	6.845	-	6.74
	13993	200 krad	7.495	7.465	7.525	-	7.41
	13964	100 krad	7.25	7.19	-	-	7.175
	13974	100 krad	7.235	7.2	-	-	7.17
Radiation $\Delta$ (%)							
	DUT	Total Dose	Pre-rad	100 krad	200 krad	300 krad	Post-ann
	14004	300 krad	-	-0.51%	0.44%	10.98%	-0.44%
	14015	300 krad	-	-0.35%	0.56%	16.82%	0.42%
	13992	200 krad	-	-0.44%	0.59%	-	-0.96%
	13993	200 krad	-	-0.40%	0.40%	-	-1.13%
	13964	100 krad	-	-0.83%	-	-	-1.03%
	13974	100 krad	-	-0.48%	-	-	-0.90%

## G. Transition Characteristics

Figure 9a to Figure 20b show the pre-irradiation and post-annealing transition edges. In each case, the radiation-induced transition-time degradation is insignificant.



Figure 9a DUT 14004 Pre-Irradiation Rising Edge



Figure 9b DUT 14004 Post-Annealing Rising Edge

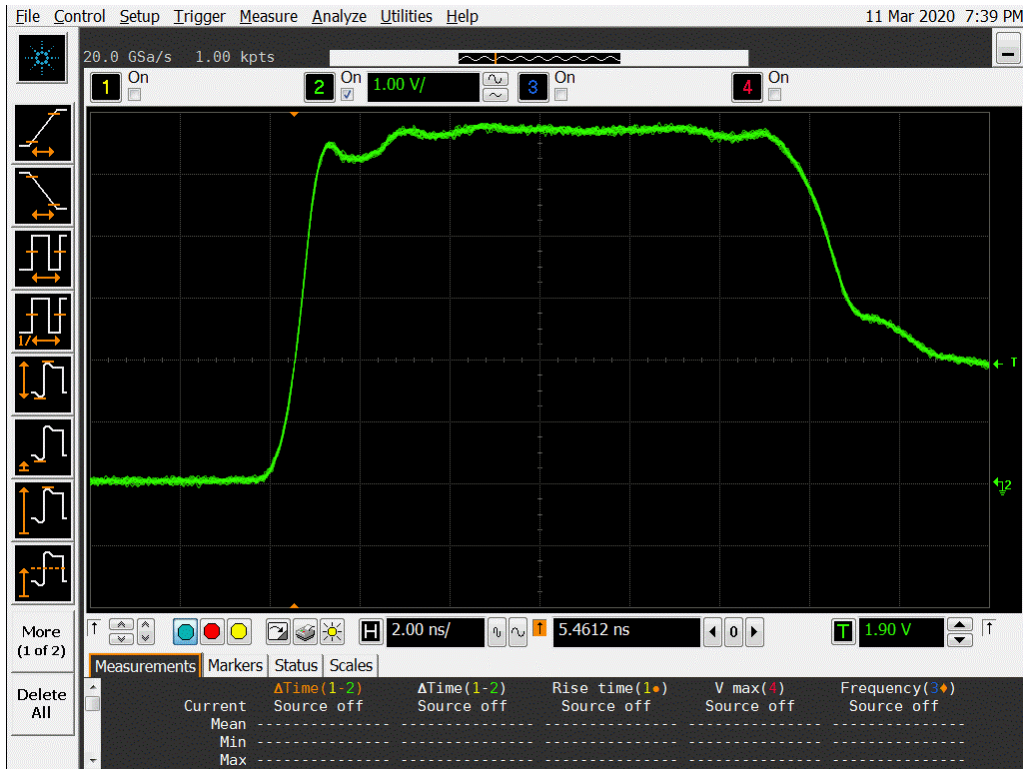


Figure 10a DUT 14015 Pre-Irradiation Rising Edge

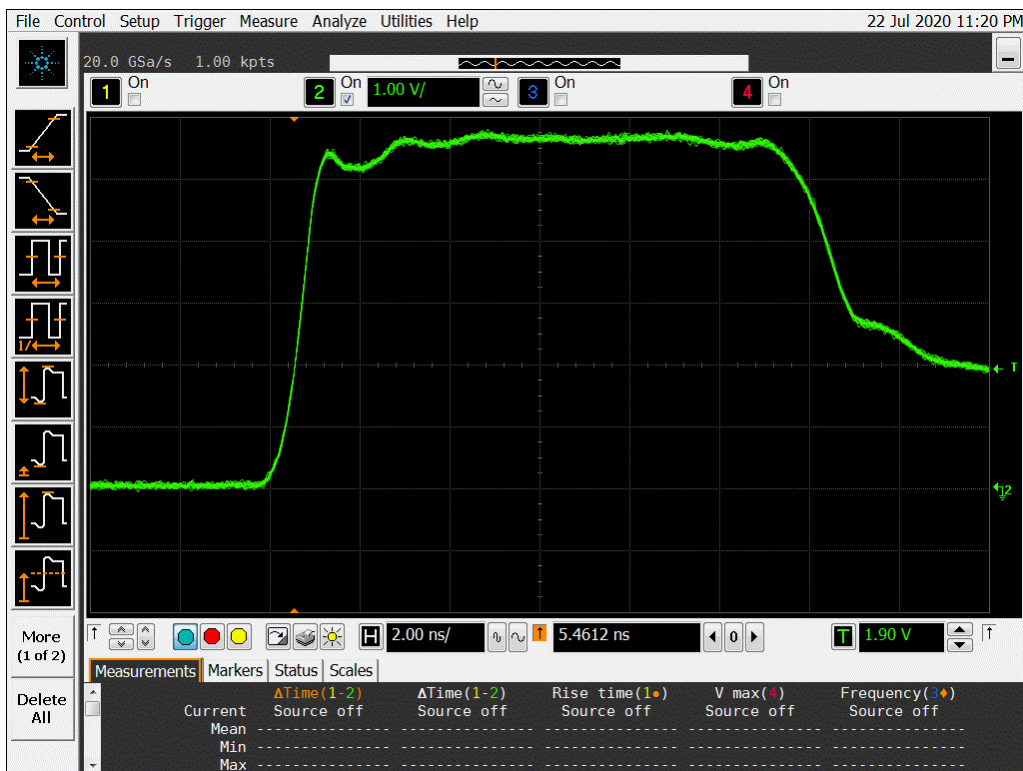
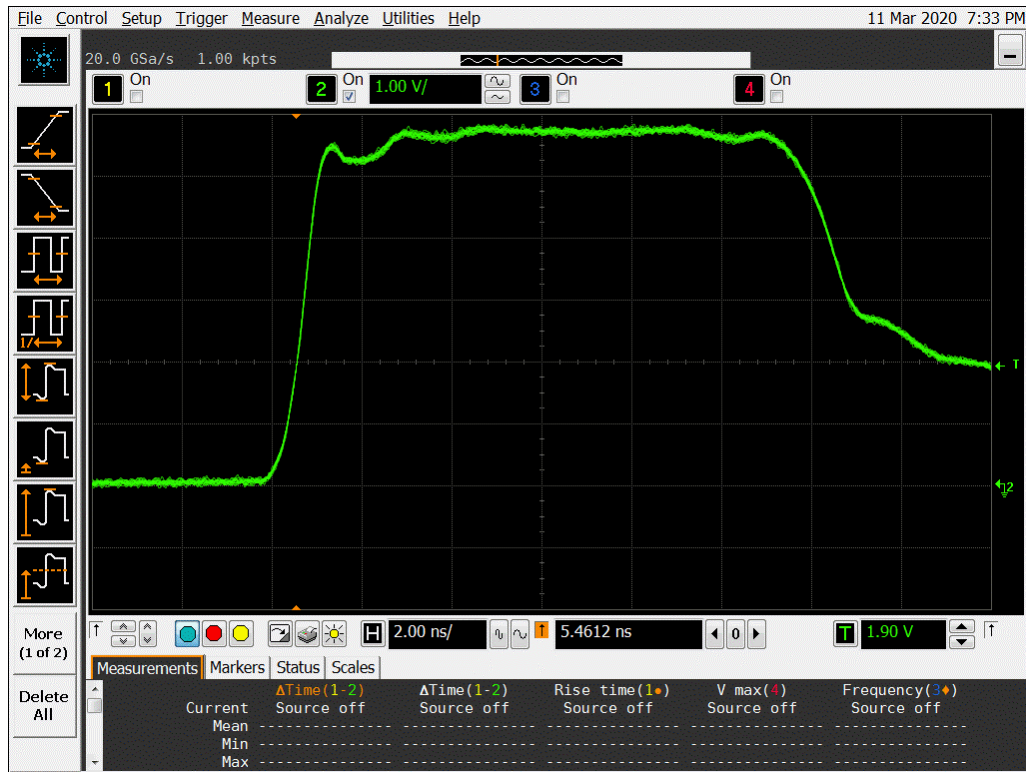


Figure 10b DUT 14015 Post-Annealing Rising Edge




**Figure 11a DUT 13992 Pre-Radiation Rising Edge**

**Figure 11b DUT 13992 Post-Annealing Rising edge**

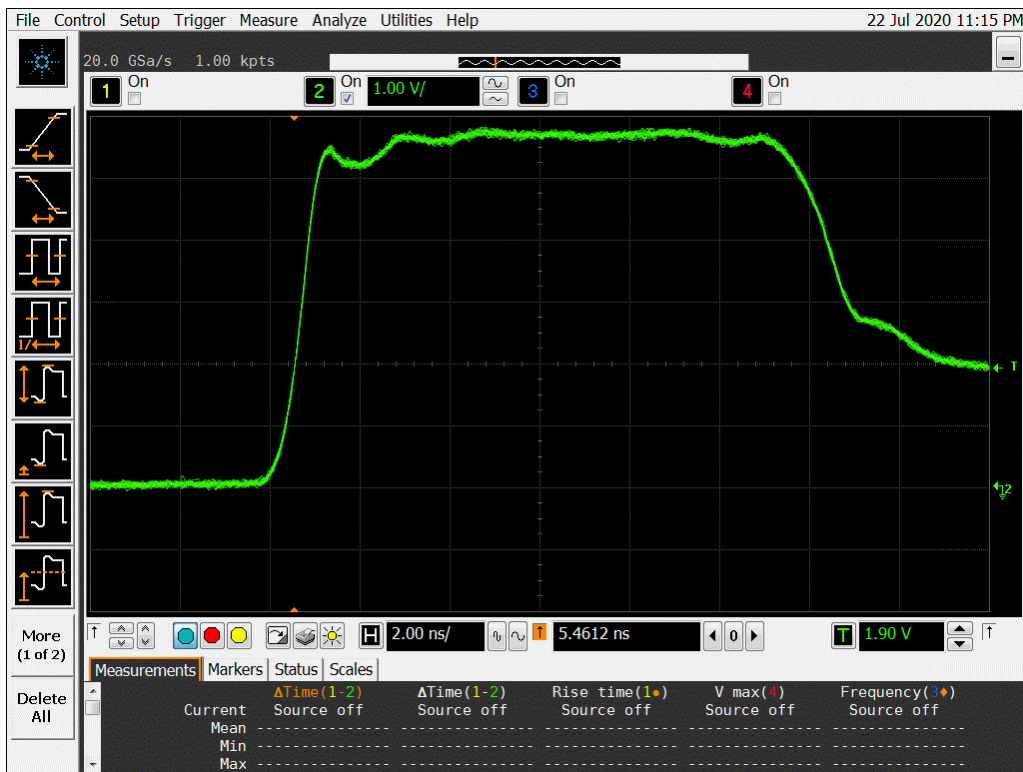

**Figure 12a DUT 13993 Pre-Irradiation Rising Edge**

**Figure 12b DUT 13993 Post-Annealing Rising Edge**



Figure 13a DUT 13964 Pre-Irradiation Rising Edge

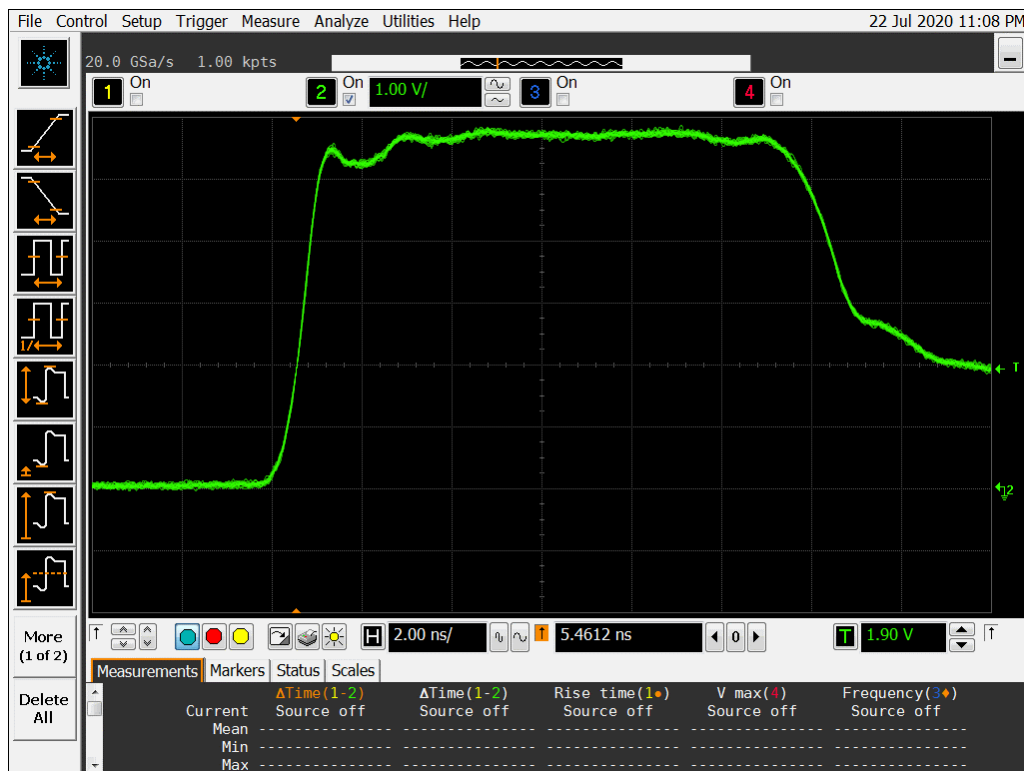
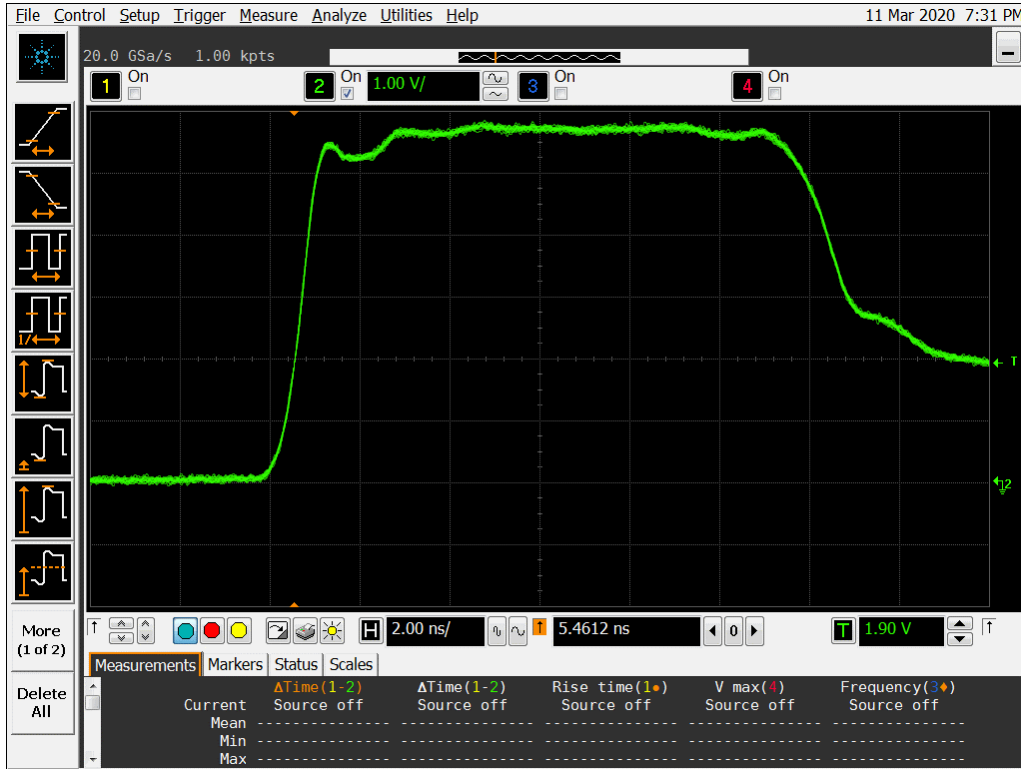
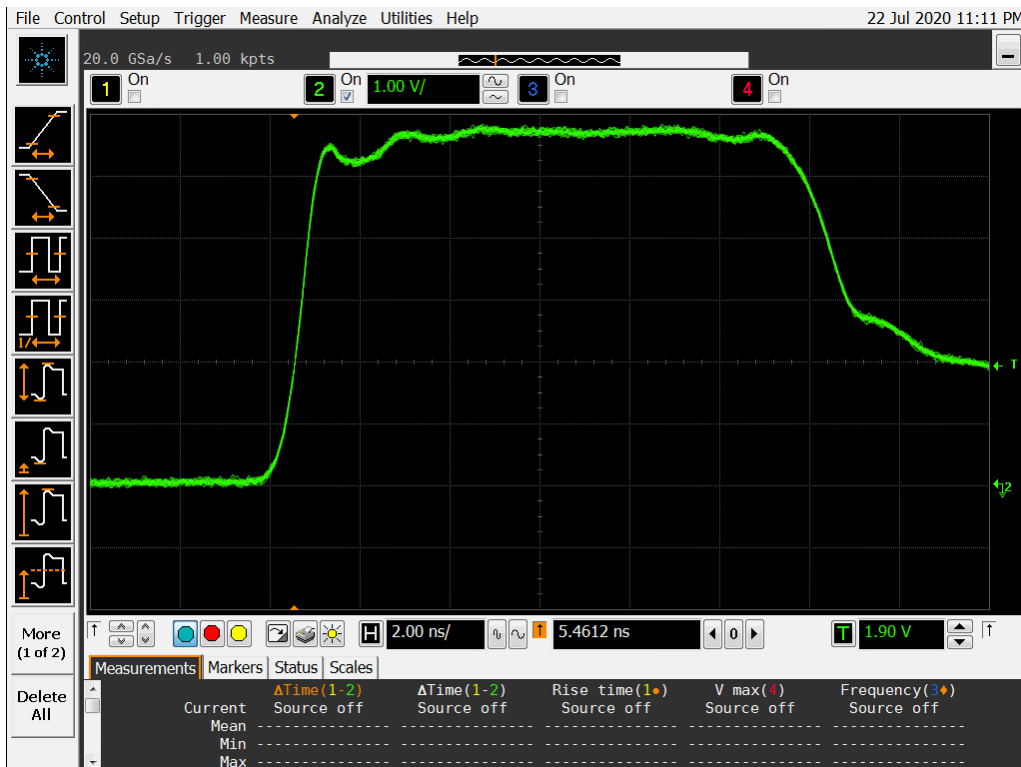
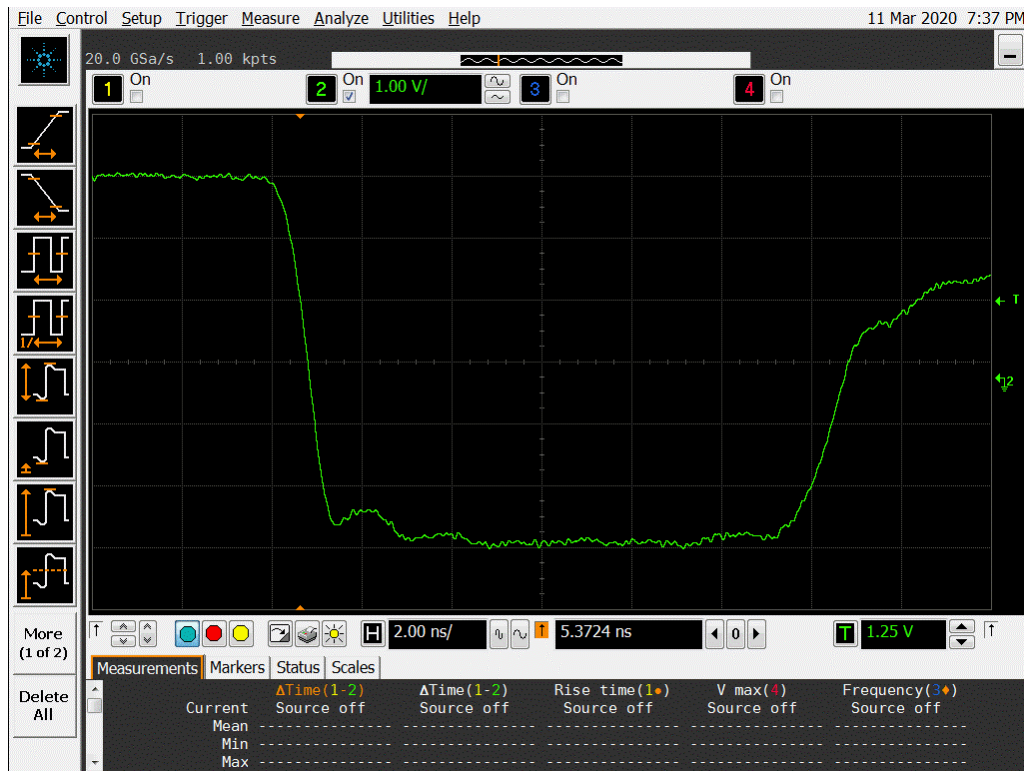


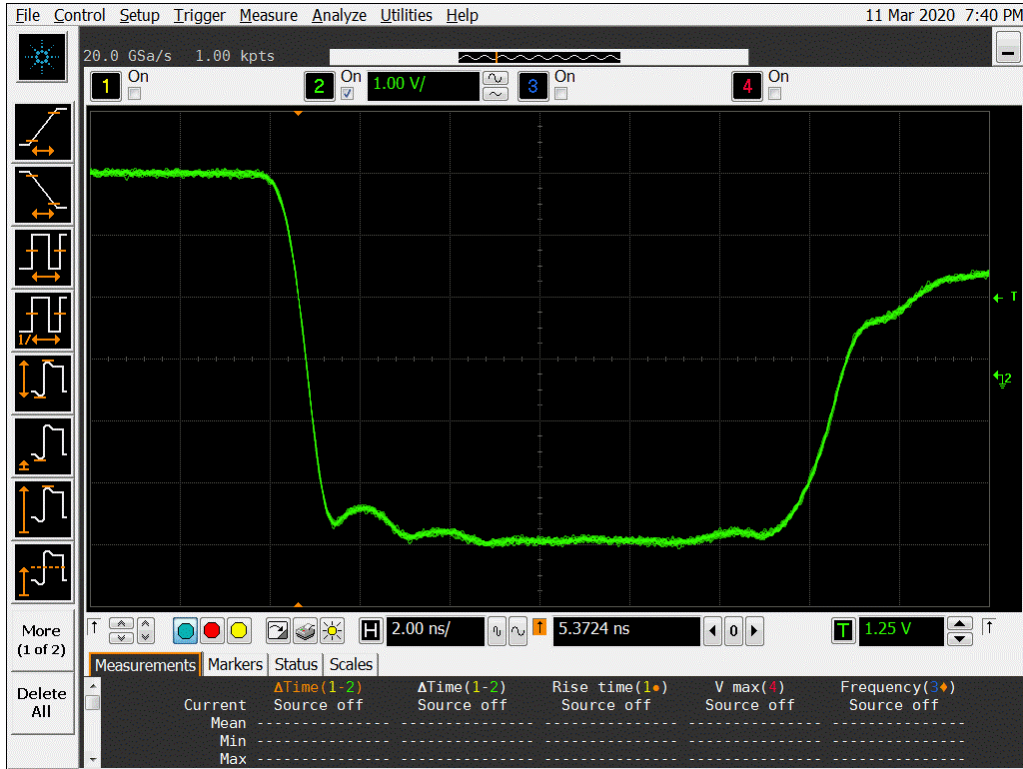
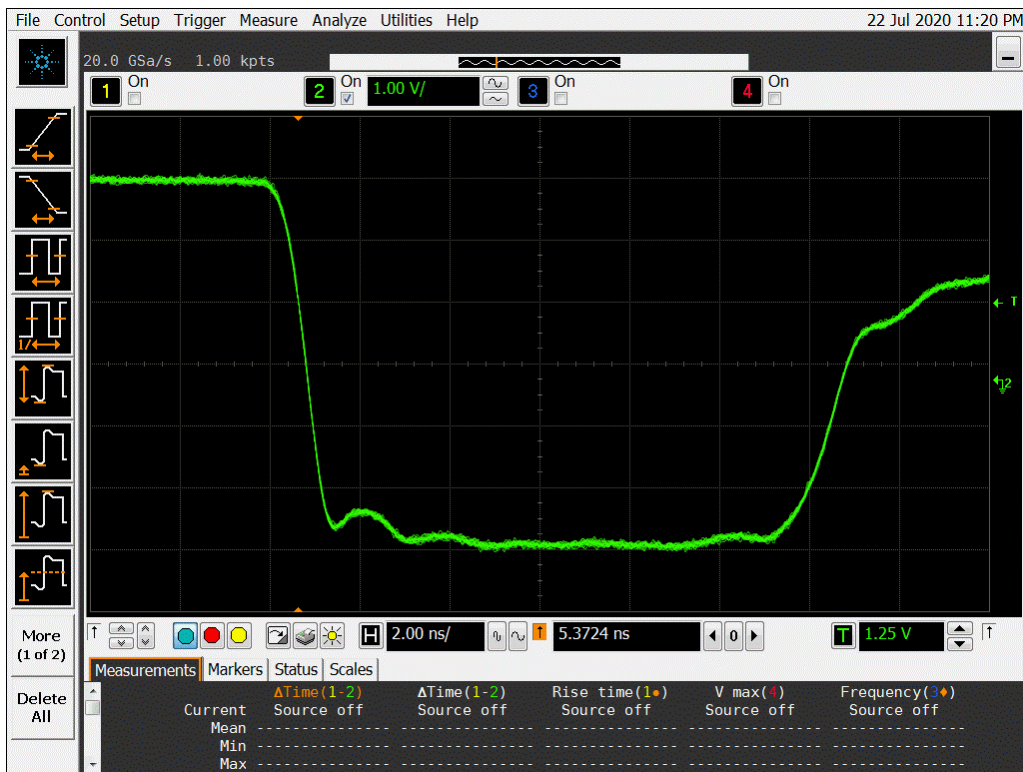
Figure 13b DUT 13964 Post-Annealing Rising Edge


**Figure 14a DUT 13974 Pre-Irradiation Rising Edge**

**Figure 14b DUT 13974 Post-Annealing Rising Edge**


**Figure 15a DUT 14004 Pre-Radiation Falling Edge**

**Figure 15b DUT 14004 Post-Annealing Falling Edge**




**Figure 16a DUT 14015 Pre-Irradiation Falling Edge**

**Figure 16b DUT 14015 Post-Annealing Falling Edge**

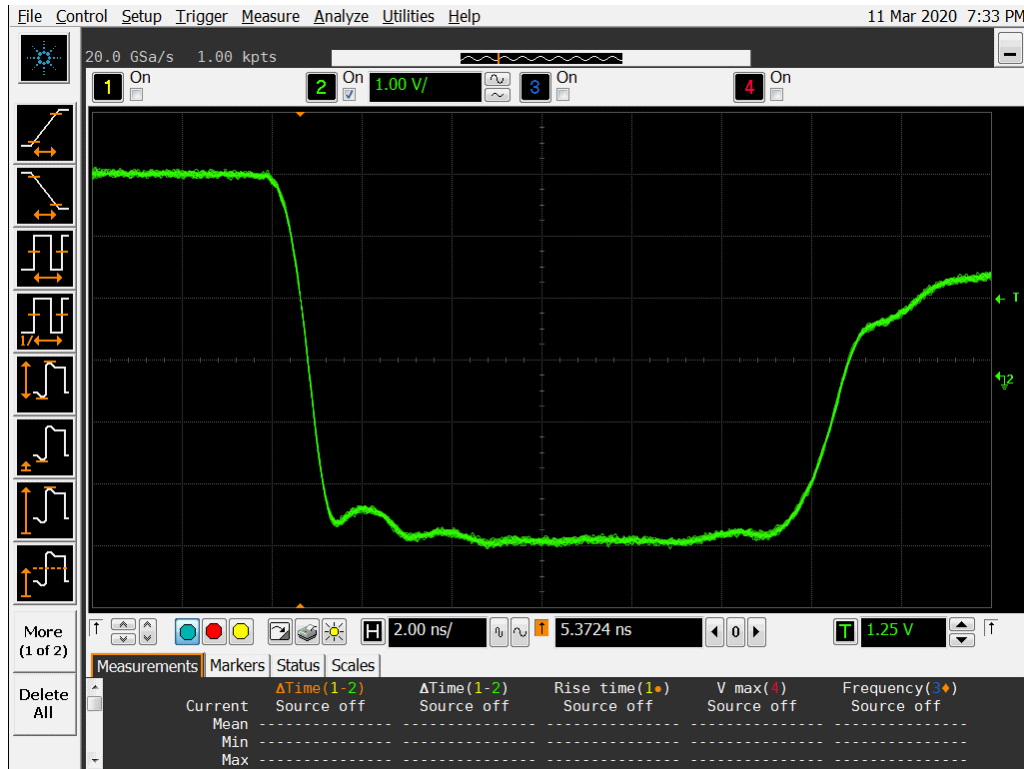


Figure 17a DUT 13992 Pre-Irradiation Falling Edge

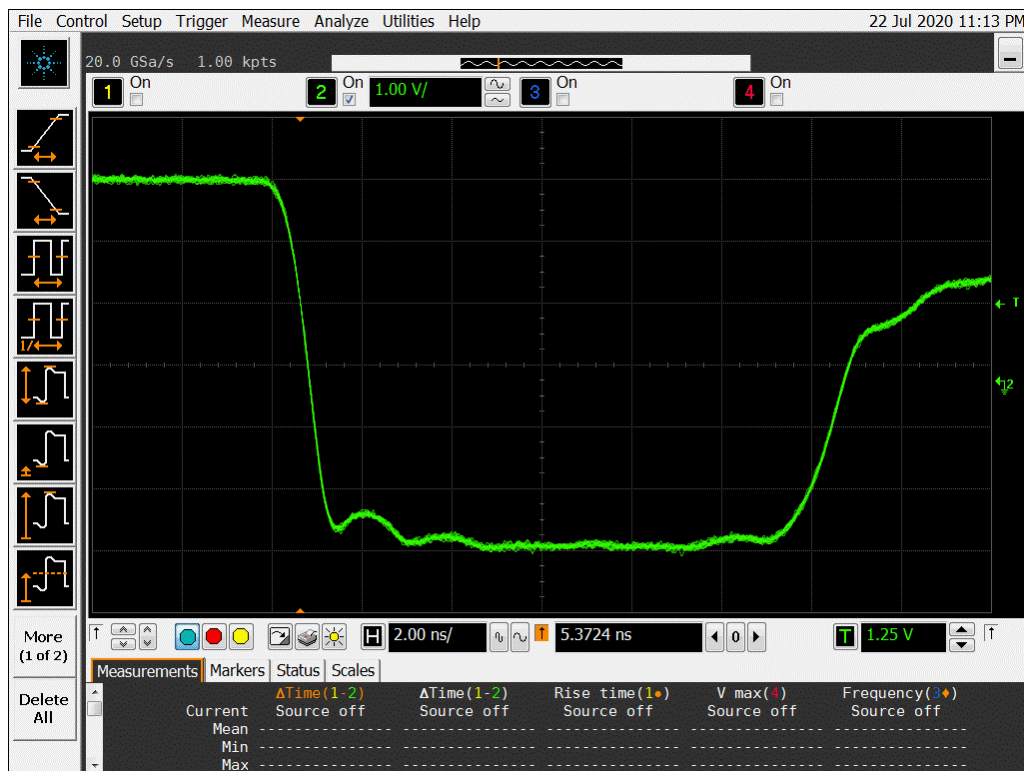
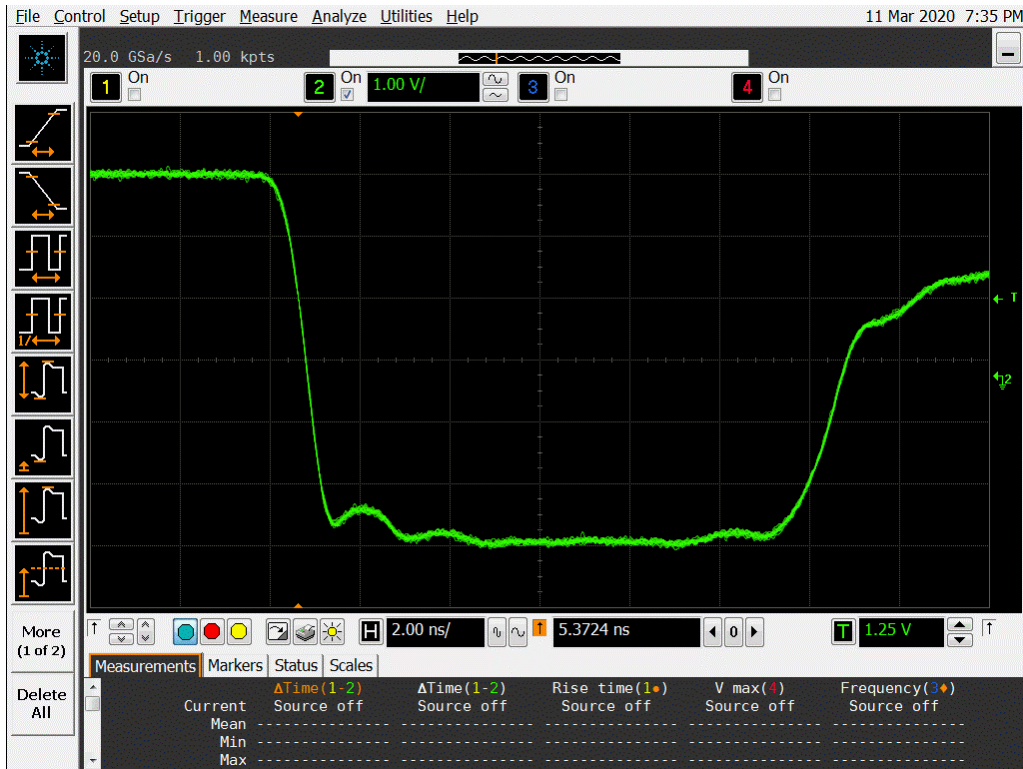
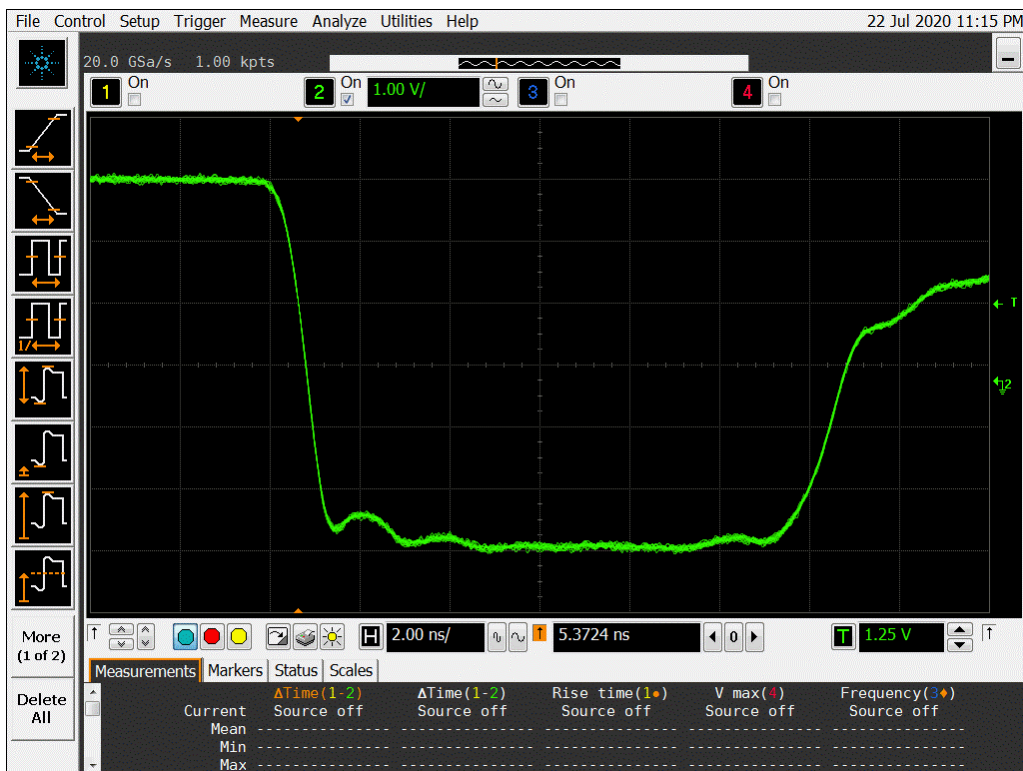


Figure 17b DUT 13992 Post-Annealing Falling Edge



**Figure 18a DUT 13993 Pre-Irradiation Falling Edge**



**Figure 18b DUT 13993 Post-Annealing Falling Edge**



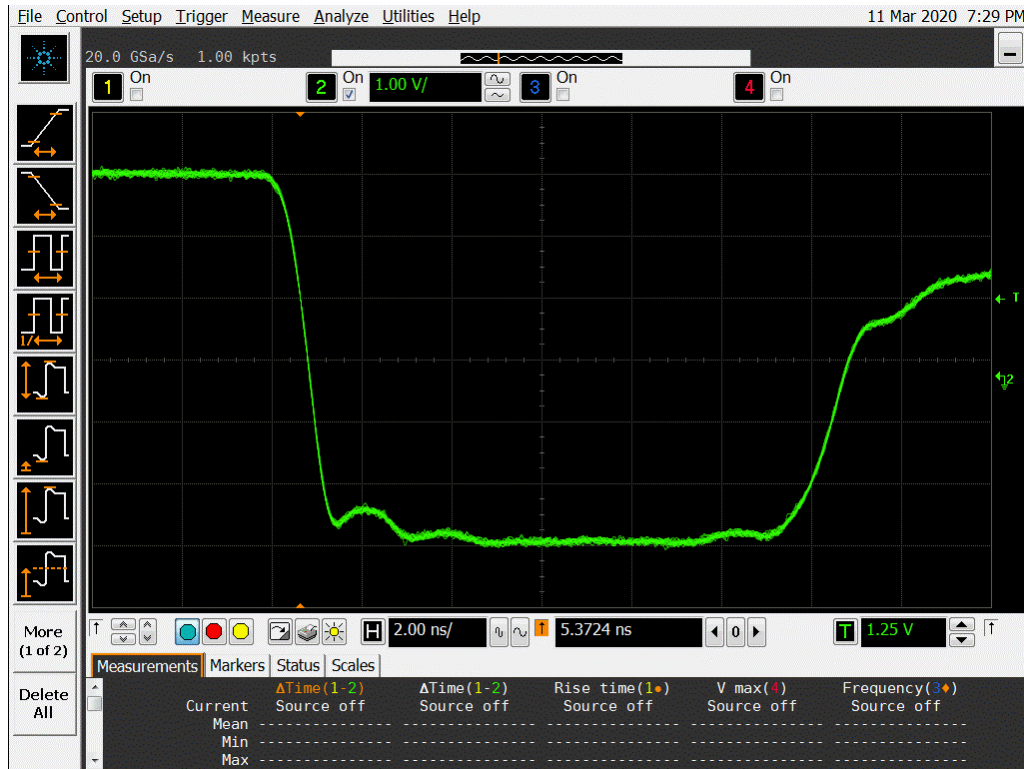


Figure 19a DUT 13964 Pre-Irradiation Falling Edge



Figure 19b DUT 13964 Post-Annealing Falling Edge

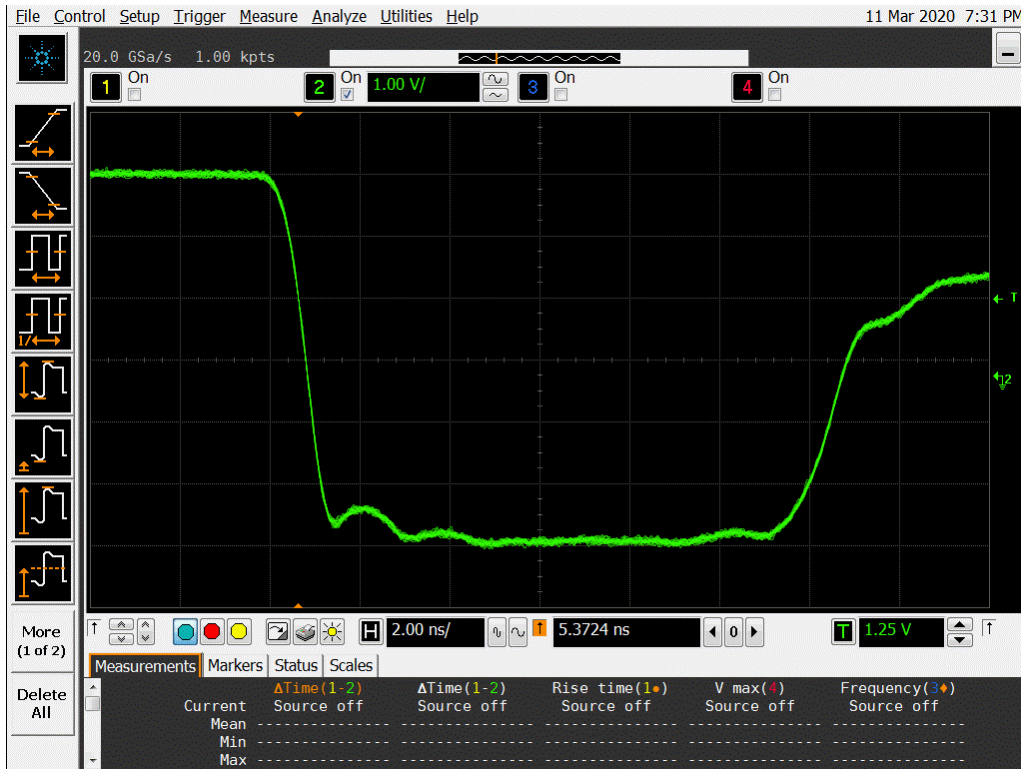


Figure 20a DUT 13974 Pre-Irradiation Falling Edge

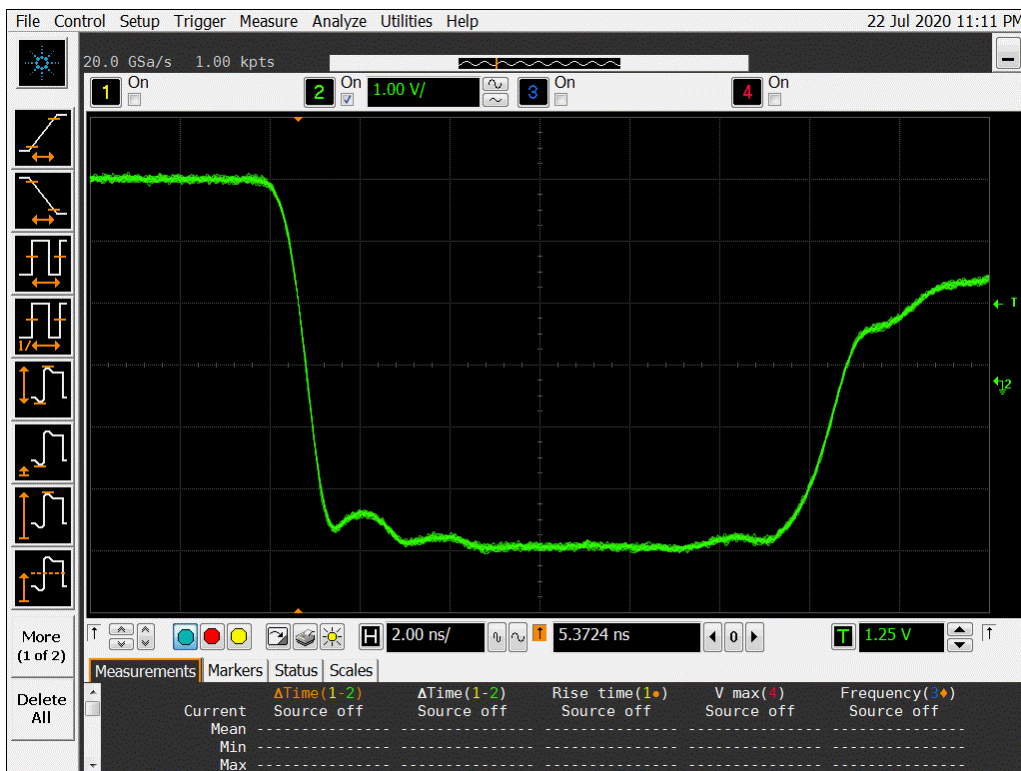


Figure 20b DUT 13974 Post-Annealing Falling Edge

## Appendix A: DUT Bias



Figure A1 I/O Bias During Irradiation

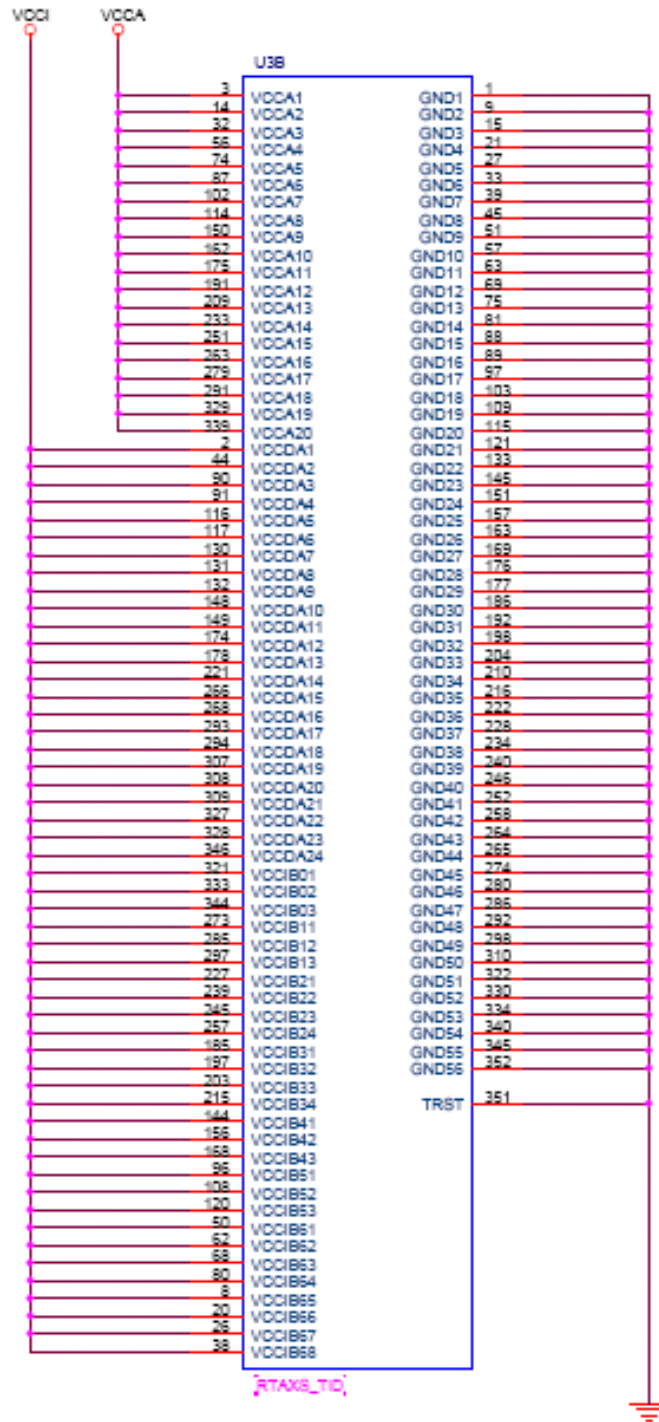
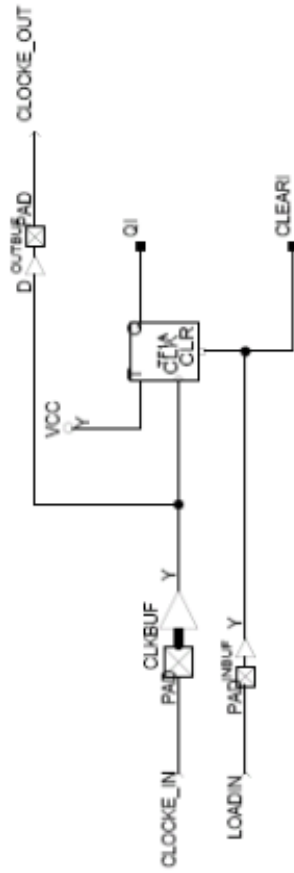
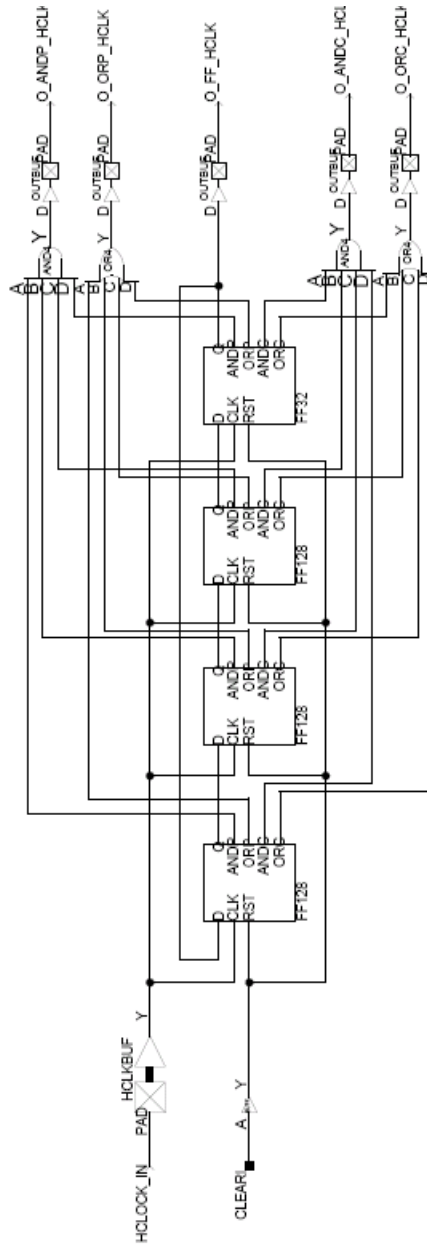
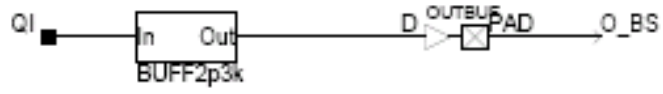


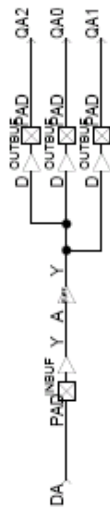
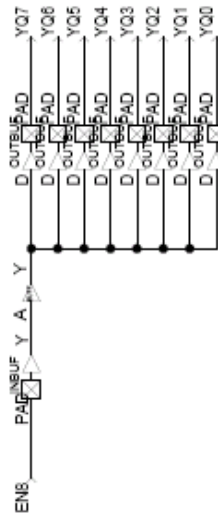
Figure A2 Power Supply, Ground and Special Pins Bias During Irradiation

## Appendix B: DUT Design Schematics and Verilog Files

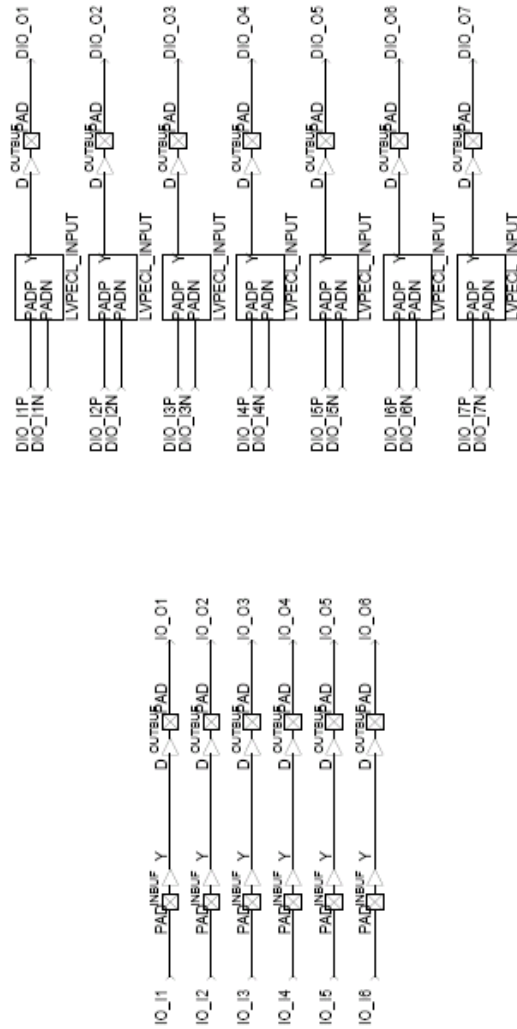


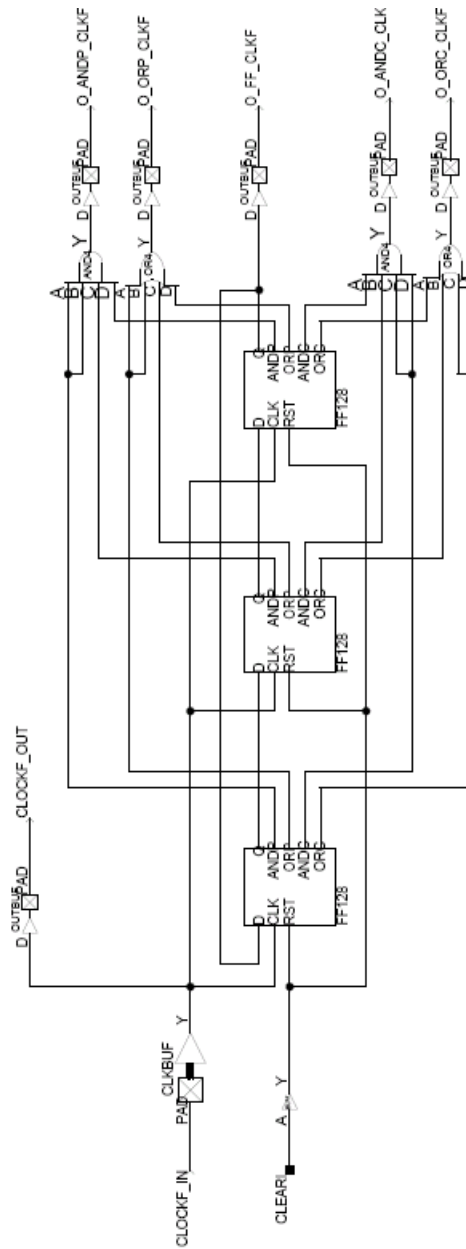


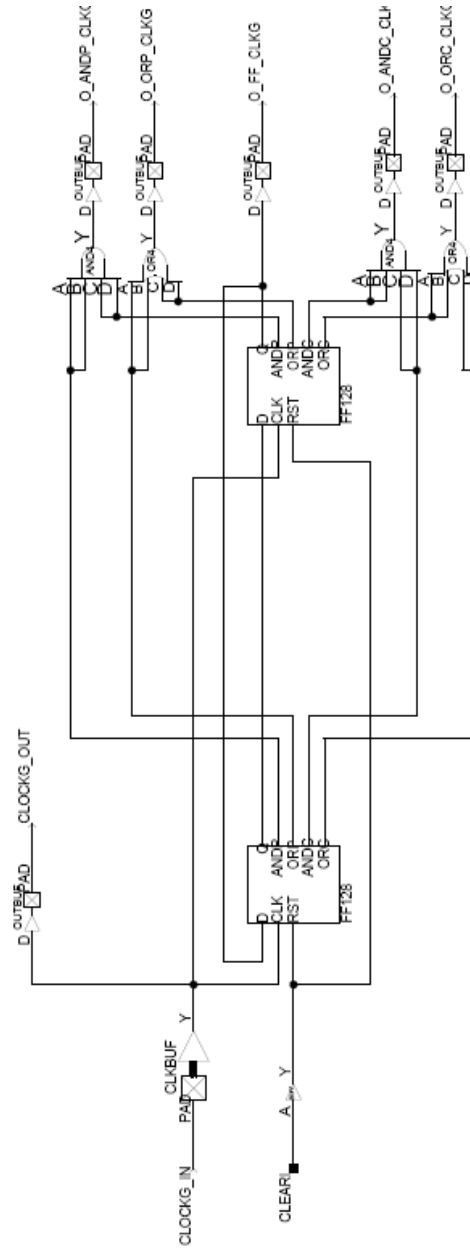


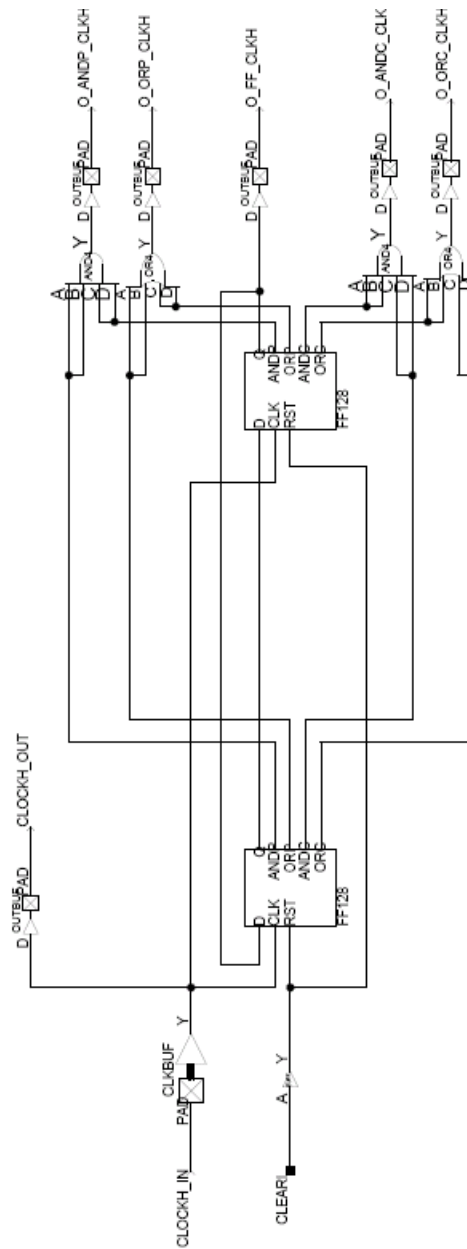












```
// BUFF2p3k.v
`timescale 1 ns/100ps

module BUFF2p3k(In, Out);

input In;

output Out;

wire x1/*synthesis syn_keep=1 lspreserve=1*/;
wire x2/*synthesis syn_keep=1 lspreserve=1*/;
wire x3/*synthesis syn_keep=1 lspreserve=1*/;
wire x4/*synthesis syn_keep=1 lspreserve=1*/;
wire x5/*synthesis syn_keep=1 lspreserve=1*/;
wire x6/*synthesis syn_keep=1 lspreserve=1*/;
wire x7/*synthesis syn_keep=1 lspreserve=1*/;

BUFF1k buff1k_1(.In(In), .Out(x1));
BUFF1k buff1k_2(.In(x1), .Out(x2));
BUFF50 buff3(.In(x2), .Out(x3));
BUFF50 buff4(.In(x3), .Out(x4));
BUFF50 buff5(.In(x4), .Out(x5));
BUFF50 buff6(.In(x5), .Out(x6));
BUFF50 buff7(.In(x6), .Out(x7));
BUFF50 buff8(.In(x7), .Out(Out));

endmodule

// BUFF1k
`timescale 1 ns/100ps

module BUFF1k(In, Out);

input In;

output Out;

wire x1/*synthesis syn_keep=1 lspreserve=1*/;
wire x2/*synthesis syn_keep=1 lspreserve=1*/;
wire x3/*synthesis syn_keep=1 lspreserve=1*/;
wire x4/*synthesis syn_keep=1 lspreserve=1*/;
wire x5/*synthesis syn_keep=1 lspreserve=1*/;
wire x6/*synthesis syn_keep=1 lspreserve=1*/;
wire x7/*synthesis syn_keep=1 lspreserve=1*/;
wire x8/*synthesis syn_keep=1 lspreserve=1*/;
wire x9/*synthesis syn_keep=1 lspreserve=1*/;
wire x10/*synthesis syn_keep=1 lspreserve=1*/;
wire x11/*synthesis syn_keep=1 lspreserve=1*/;
wire x12/*synthesis syn_keep=1 lspreserve=1*/;
wire x13/*synthesis syn_keep=1 lspreserve=1*/;
wire x14/*synthesis syn_keep=1 lspreserve=1*/;
wire x15/*synthesis syn_keep=1 lspreserve=1*/;
wire x16/*synthesis syn_keep=1 lspreserve=1*/;
wire x17/*synthesis syn_keep=1 lspreserve=1*/;
wire x18/*synthesis syn_keep=1 lspreserve=1*/;
wire x19/*synthesis syn_keep=1 lspreserve=1*/;
```

```
BUFF50 buff1 (.In(In), .Out(x1));
BUFF50 buff2 (.In(x1), .Out(x2));
BUFF50 buff3 (.In(x2), .Out(x3));
BUFF50 buff4 (.In(x3), .Out(x4));
BUFF50 buff5 (.In(x4), .Out(x5));
BUFF50 buff6 (.In(x5), .Out(x6));
BUFF50 buff7 (.In(x6), .Out(x7));
BUFF50 buff8 (.In(x7), .Out(x8));
BUFF50 buff9 (.In(x8), .Out(x9));
BUFF50 buff10 (.In(x9), .Out(x10));
```

```
BUFF50 buff11 (.In(x10), .Out(x11));
BUFF50 buff12 (.In(x11), .Out(x12));
BUFF50 buff13 (.In(x12), .Out(x13));
BUFF50 buff14 (.In(x13), .Out(x14));
BUFF50 buff15 (.In(x14), .Out(x15));
BUFF50 buff16 (.In(x15), .Out(x16));
BUFF50 buff17 (.In(x16), .Out(x17));
BUFF50 buff18 (.In(x17), .Out(x18));
BUFF50 buff19 (.In(x18), .Out(x19));
BUFF50 buff20 (.In(x19), .Out(Out));
```

```
endmodule
```

```
// BUFF50
```

```
`timescale 1 ns/100ps
```

```
module BUFF50 (In, Out);
```

```
input In;
```

```
output Out;
```

```
wire x1 /*synthesis syn_keep=1 alspreserve=1*/;
wire x2 /*synthesis syn_keep=1 alspreserve=1*/;
wire x3 /*synthesis syn_keep=1 alspreserve=1*/;
wire x4 /*synthesis syn_keep=1 alspreserve=1*/;
wire x5 /*synthesis syn_keep=1 alspreserve=1*/;
wire x6 /*synthesis syn_keep=1 alspreserve=1*/;
wire x7 /*synthesis syn_keep=1 alspreserve=1*/;
wire x8 /*synthesis syn_keep=1 alspreserve=1*/;
wire x9 /*synthesis syn_keep=1 alspreserve=1*/;
wire x10 /*synthesis syn_keep=1 alspreserve=1*/;
wire x11 /*synthesis syn_keep=1 alspreserve=1*/;
wire x12 /*synthesis syn_keep=1 alspreserve=1*/;
wire x13 /*synthesis syn_keep=1 alspreserve=1*/;
wire x14 /*synthesis syn_keep=1 alspreserve=1*/;
wire x15 /*synthesis syn_keep=1 alspreserve=1*/;
wire x16 /*synthesis syn_keep=1 alspreserve=1*/;
wire x17 /*synthesis syn_keep=1 alspreserve=1*/;
wire x18 /*synthesis syn_keep=1 alspreserve=1*/;
wire x19 /*synthesis syn_keep=1 alspreserve=1*/;
wire x20 /*synthesis syn_keep=1 alspreserve=1*/;
wire x21 /*synthesis syn_keep=1 alspreserve=1*/;
wire x22 /*synthesis syn_keep=1 alspreserve=1*/;
```

```
wire x23/*synthesis syn_keep=1 alspreserve=1*/;  
wire x24/*synthesis syn_keep=1 alspreserve=1*/;  
wire x25/*synthesis syn_keep=1 alspreserve=1*/;  
wire x26/*synthesis syn_keep=1 alspreserve=1*/;  
wire x27/*synthesis syn_keep=1 alspreserve=1*/;  
wire x28/*synthesis syn_keep=1 alspreserve=1*/;  
wire x29/*synthesis syn_keep=1 alspreserve=1*/;  
wire x30/*synthesis syn_keep=1 alspreserve=1*/;  
wire x31/*synthesis syn_keep=1 alspreserve=1*/;  
wire x32/*synthesis syn_keep=1 alspreserve=1*/;  
wire x33/*synthesis syn_keep=1 alspreserve=1*/;  
wire x34/*synthesis syn_keep=1 alspreserve=1*/;  
wire x35/*synthesis syn_keep=1 alspreserve=1*/;  
wire x36/*synthesis syn_keep=1 alspreserve=1*/;  
wire x37/*synthesis syn_keep=1 alspreserve=1*/;  
wire x38/*synthesis syn_keep=1 alspreserve=1*/;  
wire x39/*synthesis syn_keep=1 alspreserve=1*/;  
wire x40/*synthesis syn_keep=1 alspreserve=1*/;  
wire x41/*synthesis syn_keep=1 alspreserve=1*/;  
wire x42/*synthesis syn_keep=1 alspreserve=1*/;  
wire x43/*synthesis syn_keep=1 alspreserve=1*/;  
wire x44/*synthesis syn_keep=1 alspreserve=1*/;  
wire x45/*synthesis syn_keep=1 alspreserve=1*/;  
wire x46/*synthesis syn_keep=1 alspreserve=1*/;  
wire x47/*synthesis syn_keep=1 alspreserve=1*/;  
wire x48/*synthesis syn_keep=1 alspreserve=1*/;  
wire x49/*synthesis syn_keep=1 alspreserve=1*/;
```

```
BUFF buff1 (.A(In), .Y(x1));  
BUFF buff2 (.A(x1), .Y(x2));  
BUFF buff3 (.A(x2), .Y(x3));  
BUFF buff4 (.A(x3), .Y(x4));  
BUFF buff5 (.A(x4), .Y(x5));  
BUFF buff6 (.A(x5), .Y(x6));  
BUFF buff7 (.A(x6), .Y(x7));  
BUFF buff8 (.A(x7), .Y(x8));  
BUFF buff9 (.A(x8), .Y(x9));  
BUFF buff10 (.A(x9), .Y(x10));
```

```
BUFF buff11 (.A(x10), .Y(x11));  
BUFF buff12 (.A(x11), .Y(x12));  
BUFF buff13 (.A(x12), .Y(x13));  
BUFF buff14 (.A(x13), .Y(x14));  
BUFF buff15 (.A(x14), .Y(x15));  
BUFF buff16 (.A(x15), .Y(x16));  
BUFF buff17 (.A(x16), .Y(x17));  
BUFF buff18 (.A(x17), .Y(x18));  
BUFF buff19 (.A(x18), .Y(x19));  
BUFF buff20 (.A(x19), .Y(x20));
```

```
BUFF buff21 (.A(x20), .Y(x21));  
BUFF buff22 (.A(x21), .Y(x22));  
BUFF buff23 (.A(x22), .Y(x23));  
BUFF buff24 (.A(x23), .Y(x24));  
BUFF buff25 (.A(x24), .Y(x25));  
BUFF buff26 (.A(x25), .Y(x26));
```

```
BUFFbuff27 (.A(x26), .Y(x27));  
BUFFbuff28 (.A(x27), .Y(x28));  
BUFFbuff29 (.A(x28), .Y(x29));  
BUFFbuff30 (.A(x29), .Y(x30));
```

```
BUFFbuff31 (.A(x30), .Y(x31));  
BUFFbuff32 (.A(x31), .Y(x32));  
BUFFbuff33 (.A(x32), .Y(x33));  
BUFFbuff34 (.A(x33), .Y(x34));  
BUFFbuff35 (.A(x34), .Y(x35));  
BUFFbuff36 (.A(x35), .Y(x36));  
BUFFbuff37 (.A(x36), .Y(x37));  
BUFFbuff38 (.A(x37), .Y(x38));  
BUFFbuff39 (.A(x38), .Y(x39));  
BUFFbuff40 (.A(x39), .Y(x40));
```

```
BUFFbuff41 (.A(x40), .Y(x41));  
BUFFbuff42 (.A(x41), .Y(x42));  
BUFFbuff43 (.A(x42), .Y(x43));  
BUFFbuff44 (.A(x43), .Y(x44));  
BUFFbuff45 (.A(x44), .Y(x45));  
BUFFbuff46 (.A(x45), .Y(x46));  
BUFFbuff47 (.A(x46), .Y(x47));  
BUFFbuff48 (.A(x47), .Y(x48));  
BUFFbuff49 (.A(x48), .Y(x49));  
BUFFbuff50 (.A(x49), .Y(Out));
```

```
endmodule
```

```
// FF128
```

```
`timescale 1 ns/100ps
```

```
module FF128 (D, Q, CLK, RST, ANDP, ORP, ANDC, ORC);
```

```
input D, CLK, RST;
```

```
output Q, ANDP, ORP, ANDC, ORC;
```

```
wire x1, x2, x3, Q;
```

```
wire andp_a, andp_b, andp_c, andp_d, orp_a, orp_b, orp_c, orp_d;
```

```
wire andc_a, andc_b, andc_c, andc_d, orc_a, orc_b, orc_c, orc_d;
```

```
FF32 dff_a(.D(D), .Q(x1), .CLK(CLK), .RST(RST), .ANDP(andp_a), .ORP(orp_a),  
.ANDC(andc_a), .ORC(orc_a));
```

```
FF32 dff_b(.D(x1), .Q(x2), .CLK(CLK), .RST(RST), .ANDP(andp_b), .ORP(orp_b),  
.ANDC(andc_b), .ORC(orc_b));
```

```
FF32 dff_c(.D(x2), .Q(x3), .CLK(CLK), .RST(RST), .ANDP(andp_c), .ORP(orp_c),  
.ANDC(andc_c), .ORC(orc_c));
```

```
FF32 dff_d(.D(x3), .Q(Q), .CLK(CLK), .RST(RST), .ANDP(andp_d), .ORP(orp_d),  
.ANDC(andc_d), .ORC(orc_d));
```

```
AND4 and4p (.A(andp_a), .B(andp_b), .C(andp_c), .D(andp_d), .Y(ANDP));
```

```
OR4 or4p (.A(orp_a), .B(orp_b), .C(orp_c), .D(orp_d), .Y(ORP));
```

```
AND4 and4c (.A(andc_a), .B(andc_b), .C(andc_c), .D(andc_d), .Y(ANDC));
```



```
OR4 or4c (.A(orc_a),.B(orc_b),.C(orc_c),.D(orc_d),.Y(ORC));

endmodule

// FF32
`timescale 1 ns/100ps
module FF32(D,Q,CLK,RST,ANDP,ORP,ANDC,ORC);

input D,CLK,RST;
output Q,ANDP,ORP,ANDC,ORC;

wire x1,x2,x3,Q;
wire andp_a,andp_b,andp_c,andp_d,orp_a,orp_b,orp_c,orp_d;
wire andc_a,andc_b,andc_c,andc_d,orc_a,orc_b,orc_c,orc_d;

FF8 dff_a(.D(D),.Q(x1),.CLK(CLK),.RST(RST),.ANDP(andp_a),.ORP(orp_a),
.ANDC(andc_a),.ORC(orc_a));

FF8 dff_b(.D(x1),.Q(x2),.CLK(CLK),.RST(RST),.ANDP(andp_b),.ORP(orp_b),
.ANDC(andc_b),.ORC(orc_b));

FF8 dff_c(.D(x2),.Q(x3),.CLK(CLK),.RST(RST),.ANDP(andp_c),.ORP(orp_c),
.ANDC(andc_c),.ORC(orc_c));

FF8 dff_d(.D(x3),.Q(Q),.CLK(CLK),.RST(RST),.ANDP(andp_d),.ORP(orp_d),
.ANDC(andc_d),.ORC(orc_d));

AND4 and4p(.A(andp_a),.B(andp_b),.C(andp_c),.D(andp_d),.Y(ANDP));
OR4 or4p(.A(orp_a),.B(orp_b),.C(orp_c),.D(orp_d),.Y(ORP));

AND4 and4c(.A(andc_a),.B(andc_b),.C(andc_c),.D(andc_d),.Y(ANDC));
OR4 or4c(.A(orc_a),.B(orc_b),.C(orc_c),.D(orc_d),.Y(ORC));

endmodule

// FF8
`timescale 1 ns/100ps

module FF8(D,Q,CLK,RST,ANDP,ORP,ANDC,ORC);

input D,CLK,RST;
output Q,ANDP,ORP,ANDC,ORC;

wire x1,x2,x3,x4,x5,x6,x7;

DFC1B dff1(.D(D),.Q(x1),.CLK(CLK),.CLR(RST));
DFP1B dff2(.D(x1),.Q(x2),.CLK(CLK),.PRE(RST));
DFC1B dff3(.D(x2),.Q(x3),.CLK(CLK),.CLR(RST));
DFP1B dff4(.D(x3),.Q(x4),.CLK(CLK),.PRE(RST));
DFC1B dff5(.D(x4),.Q(x5),.CLK(CLK),.CLR(RST));
DFP1B dff6(.D(x5),.Q(x6),.CLK(CLK),.PRE(RST));
DFC1B dff7(.D(x6),.Q(x7),.CLK(CLK),.CLR(RST));
DFP1B dff8(.D(x7),.Q(Q),.CLK(CLK),.PRE(RST));

AND4 and4p(.A(x2),.B(x4),.C(x6),.D(Q),.Y(ANDP));
OR4 or4p(.A(x2),.B(x4),.C(x6),.D(Q),.Y(ORP));
```

```
AND4 and4c (.A(x1), .B(x3), .C(x5), .D(x7), .Y(ANDC));  
OR4 or4c (.A(x1), .B(x3), .C(x5), .D(x7), .Y(ORC));
```

```
endmodule
```

```
//Top_RAM_Module.v  
`timescale 1 ns/100ps
```

```
module Top_RAM_Module(Psel0, Psel1, RC_en, RC_clr, RC_clk, Write, Read, Wclk, Rclk,  
    Q_RAM);  
input Psel0, Psel1, RC_en, RC_clr, RC_clk, Write, Read, Wclk, Rclk;  
output [5:0] Q_RAM;
```

```
wire Gnd, Vcc;  
wire mx0, mx1;  
wire [12:0] rc;  
wire [3:0] dec;  
wire y_0w, y_0r, y_1w, y_1r, y_2w, y_2r, y_3w, y_3r;  
// y_4w, y_4r, y_5w, y_5r, y_6w, y_6r, y_7w, y_7r;  
wire [5:0] DIN;  
wire [5:0] Q_b0;  
wire [5:0] Q_b1;  
wire [5:0] Q_b2;  
wire [5:0] Q_b3;  
//wire [5:0] Q_b4;  
//wire [5:0] Q_b5;  
//wire [5:0] Q_b6;  
//wire [5:0] Q_b7;
```

```
GND gnd_0(.Y(Gnd));  
VCC vcc_0(.Y(Vcc));
```

```
mux_2x1 mux_0(.Data0_port(Gnd), .Data1_port(Vcc), .Sel0(Psel0), .Result(mx0));  
mux_2x1 mux_1(.Data0_port(Gnd), .Data1_port(Vcc), .Sel0(Psel1), .Result(mx1));
```

```
counter_13 counter_0(.Enable(RC_en), .Aclr(RC_clr), .Clock(RC_clk), .Q(rc));
```

```
decoder_2to4 decoder_0(.Data0(rc[11]), .Data1(rc[12]), .Eq(dec));
```

```
NAND2 nand_0w(.A(dec[0]), .B(Write), .Y(y_0w));  
NAND2 nand_0r(.A(dec[0]), .B(Read), .Y(y_0r));
```

```
ram_2048x6 ram_blk0(.Data(DIN), .Q(Q_b0), .WAddress(rc[10:0]), .RAddress(rc[10:0]),  
    .WE(y_0w), .RE(y_0r), .WClock(Wclk), .RClock(Rclk));
```

```
assign DIN[0]=mx0, DIN[1]=mx1, DIN[2]=mx0, DIN[3]=mx1, DIN[4]=mx0, DIN[5]=mx1;
```

```
NAND2 nand_1w(.A(dec[1]), .B(Write), .Y(y_1w));  
NAND2 nand_1r(.A(dec[1]), .B(Read), .Y(y_1r));
```

```
ram_2048x6 ram_blk1(.Data(DIN), .Q(Q_b1), .WAddress(rc[10:0]), .RAddress(rc[10:0]),  
    .WE(y_1w), .RE(y_1r), .WClock(Wclk), .RClock(Rclk));
```

```
NAND2 nand_2w(.A(dec[2]), .B(Write), .Y(y_2w));  
NAND2 nand_2r(.A(dec[2]), .B(Read), .Y(y_2r));
```

```
ram_2048x6 ram_blk2(.Data(DIN),
    .Q(Q_b2), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_2w), .RE(y_2r), .WClock(Wclk), .RClock(Rclk));

NAND2 nand_3w(.A(dec[3]), .B(Write), .Y(y_3w));
NAND2 nand_3r(.A(dec[3]), .B(Read), .Y(y_3r));

ram_2048x6 ram_blk3(.Data(DIN),
    .Q(Q_b3), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_3w), .RE(y_3r), .WClock(Wclk), .RClock(Rclk));

/* NAND2 nand_4w(.A(dec[4]), .B(Write), .Y(y_4w));
NAND2 nand_4r(.A(dec[4]), .B(Read), .Y(y_4r));

ram_2048x3 ram_blk4(.Data(DIN),
    .Q(Q_b4), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_4w), .RE(y_4r), .WClock(Wclk), .RClock(Rclk));

NAND2 nand_5w(.A(dec[5]), .B(Write), .Y(y_5w));
NAND2 nand_5r(.A(dec[5]), .B(Read), .Y(y_5r));

ram_2048x3 ram_blk5(.Data(DIN),
    .Q(Q_b5), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_5w), .RE(y_5r), .WClock(Wclk), .RClock(Rclk));

NAND2 nand_6w(.A(dec[6]), .B(Write), .Y(y_6w));
NAND2 nand_6r(.A(dec[6]), .B(Read), .Y(y_6r));

ram_2048x3 ram_blk6(.Data(DIN),
    .Q(Q_b6), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_6w), .RE(y_6r), .WClock(Wclk), .RClock(Rclk));

NAND2 nand_7w(.A(dec[7]), .B(Write), .Y(y_7w));
NAND2 nand_7r(.A(dec[7]), .B(Read), .Y(y_7r));

ram_2048x3 ram_blk7(.Data(DIN),
    .Q(Q_b7), .WAddress(rc[10:0]), .RAddress(rc[10:0]),
    .WE(y_7w), .RE(y_7r), .WClock(Wclk), .RClock(Rclk)); */

mux_6x4 mux_6x4_0(.Data0_port(Q_b0), .Data1_port(Q_b1), .Data2_port(Q_b2),
    .Data3_port(Q_b3), .Sel0(rc[11]),
    .Sel1(rc[12]), .Result(Q_RAM));

endmodule
```

```
`timescale 1 ns/100ps
// Version: 6.0 SP3 6.0.30.3
```

```
module mux_2x1(Data0_port,Data1_port,Sel0,Result);
input Data0_port, Data1_port, Sel0;
output Result;
```

```
    MX2 MX2_Result(.A(Data0_port),.B(Data1_port),.S(Sel0),.Y(
        Result));
```

```
endmodule
```

```
`timescale 1 ns/100ps
// Version: 6.2 SP2 6.2.52.7
```

```
module counter_13(Enable,Aclr,Clock,Q);
input Enable, Aclr, Clock;
output [12:0] Q;
```

```
wire ClrAux_0_net, ClrAux_7_net, MX2_1_Y, MX2_7_Y, MX2_4_Y,
    CM8_0_Y, MX2_10_Y, MX2_9_Y, MX2_3_Y, MX2_5_Y, MX2_6_Y,
    MX2_0_Y, MX2_8_Y, MX2_2_Y, MX2_11_Y, VCC, GND;
```

```
VCC VCC_1_net(.Y(VCC));
GND GND_1_net(.Y(GND));
DFC1D DFC1D_Q_7_inst(.D(MX2_1_Y),.CLK(Q[6]),.CLR(
    ClrAux_7_net),.Q(Q[7]));
DFC1D DFC1D_Q_1_inst(.D(MX2_7_Y),.CLK(Q[0]),.CLR(
    ClrAux_0_net),.Q(Q[1]));
BUFF BUFF_ClrAux_0_inst(.A(Aclr),.Y(ClrAux_0_net));
MX2 MX2_9(.A(VCC),.B(GND),.S(Q[5]),.Y(MX2_9_Y));
DFC1D DFC1D_Q_2_inst(.D(MX2_6_Y),.CLK(Q[1]),.CLR(
    ClrAux_0_net),.Q(Q[2]));
MX2 MX2_0(.A(VCC),.B(GND),.S(Q[8]),.Y(MX2_0_Y));
DFC1D DFC1D_Q_12_inst(.D(MX2_4_Y),.CLK(Q[11]),.CLR(
    ClrAux_7_net),.Q(Q[12]));
DFC1D DFC1D_Q_3_inst(.D(MX2_11_Y),.CLK(Q[2]),.CLR(
    ClrAux_0_net),.Q(Q[3]));
DFC1D DFC1D_Q_4_inst(.D(MX2_5_Y),.CLK(Q[3]),.CLR(
    ClrAux_0_net),.Q(Q[4]));
CM8 CM8_0(.D0(GND),.D1(VCC),.D2(VCC),.D3(GND),.S00(Q[0]),
    .S01(VCC),.S10(Enable),.S11(GND),.Y(CM8_0_Y));
MX2 MX2_11(.A(VCC),.B(GND),.S(Q[3]),.Y(MX2_11_Y));
DFC1B DFC1B_Q_0_inst(.D(CM8_0_Y),.CLK(Clock),.CLR(
    ClrAux_0_net),.Q(Q[0]));
MX2 MX2_6(.A(VCC),.B(GND),.S(Q[2]),.Y(MX2_6_Y));
MX2 MX2_3(.A(VCC),.B(GND),.S(Q[10]),.Y(MX2_3_Y));
DFC1D DFC1D_Q_11_inst(.D(MX2_10_Y),.CLK(Q[10]),.CLR(
    ClrAux_7_net),.Q(Q[11]));
MX2 MX2_10(.A(VCC),.B(GND),.S(Q[11]),.Y(MX2_10_Y));
BUFF BUFF_ClrAux_7_inst(.A(Aclr),.Y(ClrAux_7_net));
MX2 MX2_4(.A(VCC),.B(GND),.S(Q[12]),.Y(MX2_4_Y));
DFC1D DFC1D_Q_5_inst(.D(MX2_9_Y),.CLK(Q[4]),.CLR(
```

```
    ClrAux_0_net), .Q(Q[5]));
DFC1DDFC1D_Q_9_inst(.D(MX2_8_Y), .CLK(Q[8]), .CLR(
    ClrAux_7_net), .Q(Q[9]));
MX2 MX2_5(.A(VCC), .B(GND), .S(Q[4]), .Y(MX2_5_Y));
MX2 MX2_8(.A(VCC), .B(GND), .S(Q[9]), .Y(MX2_8_Y));
DFC1DDFC1D_Q_8_inst(.D(MX2_0_Y), .CLK(Q[7]), .CLR(
    ClrAux_7_net), .Q(Q[8]));
MX2 MX2_2(.A(VCC), .B(GND), .S(Q[6]), .Y(MX2_2_Y));
MX2 MX2_7(.A(VCC), .B(GND), .S(Q[1]), .Y(MX2_7_Y));
MX2 MX2_1(.A(VCC), .B(GND), .S(Q[7]), .Y(MX2_1_Y));
DFC1DDFC1D_Q_6_inst(.D(MX2_2_Y), .CLK(Q[5]), .CLR(
    ClrAux_0_net), .Q(Q[6]));
DFC1DDFC1D_Q_10_inst(.D(MX2_3_Y), .CLK(Q[9]), .CLR(
    ClrAux_7_net), .Q(Q[10]));

endmodule

`timescale 1 ns/100 ps
// Version: 6.2 SP2 6.2.52.7

module decoder_2to4(Data0,Data1,Eq);
input Data0, Data1;
output [3:0] Eq;

    AND2A AND2A_Eq_1_inst(.A(Data1), .B(Data0), .Y(Eq[1]));
    AND2 AND2_Eq_3_inst(.A(Data0), .B(Data1), .Y(Eq[3]));
    AND2A AND2A_Eq_2_inst(.A(Data0), .B(Data1), .Y(Eq[2]));
    AND2B AND2B_Eq_0_inst(.A(Data0), .B(Data1), .Y(Eq[0]));

endmodule

`timescale 1 ns/100 ps
// Version: 6.2 SP2 6.2.52.7

module ram_2048x6(Data,Q,WAddress,RAddress,WE,RE,WClk,RClk);
input [5:0] Data;
output [5:0] Q;
input [10:0] WAddress, RAddress;
input WE, RE, WClk, RClk;

    wire WEP, REP, VCC, GND;

    VCC VCC_1_net(.Y(VCC));
    GND GND_1_net(.Y(GND));
    RAM64K36P ram_2048x6_R0C2(.WCLK(WClk), .RCLK(RClk),
        .DEPTH0(GND), .DEPTH1(GND), .DEPTH2(GND), .DEPTH3(GND),
        .WEN(WEP), .WW0(VCC), .WW1(GND), .WW2(GND), .WRAD0(
        WAddress[0]), .WRAD1(WAddress[1]), .WRAD2(WAddress[2]),
        .WRAD3(WAddress[3]), .WRAD4(WAddress[4]), .WRAD5(
        WAddress[5]), .WRAD6(WAddress[6]), .WRAD7(WAddress[7]),
        .WRAD8(WAddress[8]), .WRAD9(WAddress[9]), .WRAD10(
        WAddress[10]), .WRAD11(GND), .WRAD12(GND), .WRAD13(GND),
        .WRAD14(GND), .WRAD15(GND), .WD0(Data[4]), .WD1(Data[5]),
```

.WD2(GND), .WD3(GND), .WD4(GND), .WD5(GND), .WD6(GND),  
.WD7(GND), .WD8(GND), .WD9(GND), .WD10(GND), .WD11(GND),  
.WD12(GND), .WD13(GND), .WD14(GND), .WD15(GND), .WD16(GND)  
, .WD17(GND), .WD18(GND), .WD19(GND), .WD20(GND), .WD21(  
GND), .WD22(GND), .WD23(GND), .WD24(GND), .WD25(GND),  
.WD26(GND), .WD27(GND), .WD28(GND), .WD29(GND), .WD30(GND)  
, .WD31(GND), .WD32(GND), .WD33(GND), .WD34(GND), .WD35(  
GND), .REN(REP), .RW0(VCC), .RW1(GND), .RW2(GND), .RDAD0(  
RAddress[0]), .RDAD1(RAddress[1]), .RDAD2(RAddress[2]),  
.RDAD3(RAddress[3]), .RDAD4(RAddress[4]), .RDAD5(  
RAddress[5]), .RDAD6(RAddress[6]), .RDAD7(RAddress[7]),  
.RDAD8(RAddress[8]), .RDAD9(RAddress[9]), .RDAD10(  
RAddress[10]), .RDAD11(GND), .RDAD12(GND), .RDAD13(GND),  
.RDAD14(GND), .RDAD15(GND), .RD0(Q[4]), .RD1(Q[5]), .RD2(  
, .RD3(), .RD4(), .RD5(), .RD6(), .RD7(), .RD8(), .RD9(),  
.RD10(), .RD11(), .RD12(), .RD13(), .RD14(), .RD15(),  
.RD16(), .RD17(), .RD18(), .RD19(), .RD20(), .RD21(),  
.RD22(), .RD23(), .RD24(), .RD25(), .RD26(), .RD27(),  
.RD28(), .RD29(), .RD30(), .RD31(), .RD32(), .RD33(),  
.RD34(), .RD35());  
INV REBUBBLE(.A(RE), .Y(REP));  
INV WEBUBBLE(.A(WE), .Y(WEP));  
RAM64K36Pram\_2048x6\_R0C1(.WCLK(WClock), .RCLK(RClock),  
.DEPTH0(GND), .DEPTH1(GND), .DEPTH2(GND), .DEPTH3(GND),  
.WEN(WEP), .WW0(VCC), .WW1(GND), .WW2(GND), .WRAD0(  
WAddress[0]), .WRAD1(WAddress[1]), .WRAD2(WAddress[2]),  
.WRAD3(WAddress[3]), .WRAD4(WAddress[4]), .WRAD5(  
WAddress[5]), .WRAD6(WAddress[6]), .WRAD7(WAddress[7]),  
.WRAD8(WAddress[8]), .WRAD9(WAddress[9]), .WRAD10(  
WAddress[10]), .WRAD11(GND), .WRAD12(GND), .WRAD13(GND),  
.WRAD14(GND), .WRAD15(GND), .WD0(Data[2]), .WD1(Data[3]),  
.WD2(GND), .WD3(GND), .WD4(GND), .WD5(GND), .WD6(GND),  
.WD7(GND), .WD8(GND), .WD9(GND), .WD10(GND), .WD11(GND),  
.WD12(GND), .WD13(GND), .WD14(GND), .WD15(GND), .WD16(GND)  
, .WD17(GND), .WD18(GND), .WD19(GND), .WD20(GND), .WD21(  
GND), .WD22(GND), .WD23(GND), .WD24(GND), .WD25(GND),  
.WD26(GND), .WD27(GND), .WD28(GND), .WD29(GND), .WD30(GND)  
, .WD31(GND), .WD32(GND), .WD33(GND), .WD34(GND), .WD35(  
GND), .REN(REP), .RW0(VCC), .RW1(GND), .RW2(GND), .RDAD0(  
RAddress[0]), .RDAD1(RAddress[1]), .RDAD2(RAddress[2]),  
.RDAD3(RAddress[3]), .RDAD4(RAddress[4]), .RDAD5(  
RAddress[5]), .RDAD6(RAddress[6]), .RDAD7(RAddress[7]),  
.RDAD8(RAddress[8]), .RDAD9(RAddress[9]), .RDAD10(  
RAddress[10]), .RDAD11(GND), .RDAD12(GND), .RDAD13(GND),  
.RDAD14(GND), .RDAD15(GND), .RD0(Q[2]), .RD1(Q[3]), .RD2(  
, .RD3(), .RD4(), .RD5(), .RD6(), .RD7(), .RD8(), .RD9(),  
.RD10(), .RD11(), .RD12(), .RD13(), .RD14(), .RD15(),  
.RD16(), .RD17(), .RD18(), .RD19(), .RD20(), .RD21(),  
.RD22(), .RD23(), .RD24(), .RD25(), .RD26(), .RD27(),  
.RD28(), .RD29(), .RD30(), .RD31(), .RD32(), .RD33(),  
.RD34(), .RD35());  
RAM64K36Pram\_2048x6\_R0C0(.WCLK(WClock), .RCLK(RClock),  
.DEPTH0(GND), .DEPTH1(GND), .DEPTH2(GND), .DEPTH3(GND),  
.WEN(WEP), .WW0(VCC), .WW1(GND), .WW2(GND), .WRAD0(  
WAddress[0]), .WRAD1(WAddress[1]), .WRAD2(WAddress[2]),  
.WRAD3(WAddress[3]), .WRAD4(WAddress[4]), .WRAD5(

```
WAddress[5]), .WRAD6(WAddress[6]), .WRAD7(WAddress[7]),  
.WRAD8(WAddress[8]), .WRAD9(WAddress[9]), .WRAD10(  
WAddress[10]), .WRAD11(GND), .WRAD12(GND), .WRAD13(GND),  
.WRAD14(GND), .WRAD15(GND), .WD0(Data[0]), .WD1(Data[1]),  
.WD2(GND), .WD3(GND), .WD4(GND), .WD5(GND), .WD6(GND),  
.WD7(GND), .WD8(GND), .WD9(GND), .WD10(GND), .WD11(GND),  
.WD12(GND), .WD13(GND), .WD14(GND), .WD15(GND), .WD16(GND)  
, .WD17(GND), .WD18(GND), .WD19(GND), .WD20(GND), .WD21(  
GND), .WD22(GND), .WD23(GND), .WD24(GND), .WD25(GND),  
.WD26(GND), .WD27(GND), .WD28(GND), .WD29(GND), .WD30(GND)  
, .WD31(GND), .WD32(GND), .WD33(GND), .WD34(GND), .WD35(  
GND), .REN(REP), .RW0(VCC), .RW1(GND), .RW2(GND), .RDAD0(  
RAddress[0]), .RDAD1(RAddress[1]), .RDAD2(RAddress[2]),  
.RDAD3(RAddress[3]), .RDAD4(RAddress[4]), .RDAD5(  
RAddress[5]), .RDAD6(RAddress[6]), .RDAD7(RAddress[7]),  
.RDAD8(RAddress[8]), .RDAD9(RAddress[9]), .RDAD10(  
RAddress[10]), .RDAD11(GND), .RDAD12(GND), .RDAD13(GND),  
.RDAD14(GND), .RDAD15(GND), .RD0(Q[0]), .RD1(Q[1]), .RD2(  
, .RD3(), .RD4(), .RD5(), .RD6(), .RD7(), .RD8(), .RD9(),  
.RD10(), .RD11(), .RD12(), .RD13(), .RD14(), .RD15(),  
.RD16(), .RD17(), .RD18(), .RD19(), .RD20(), .RD21(),  
.RD22(), .RD23(), .RD24(), .RD25(), .RD26(), .RD27(),  
.RD28(), .RD29(), .RD30(), .RD31(), .RD32(), .RD33(),  
.RD34(), .RD35());
```

endmodule

```
`timescale 1 ns/100 ps  
// Version: 6.2 SP2 6.2.52.7
```

```
module mux_6x4(Data0_port,Data1_port,Data2_port,Data3_port,Sel0,  
Sel1,Result);  
input [5:0]Data0_port, Data1_port, Data2_port, Data3_port;  
input Sel0, Sel1;  
output [5:0] Result;
```

```
MX4 MX4_Result_0_inst(.D0(Data0_port[0]), .D1(Data1_port[0]),  
.D2(Data2_port[0]), .D3(Data3_port[0]), .S0(Sel0), .S1(  
Sel1), .Y(Result[0]));  
MX4 MX4_Result_2_inst(.D0(Data0_port[2]), .D1(Data1_port[2]),  
.D2(Data2_port[2]), .D3(Data3_port[2]), .S0(Sel0), .S1(  
Sel1), .Y(Result[2]));  
MX4 MX4_Result_5_inst(.D0(Data0_port[5]), .D1(Data1_port[5]),  
.D2(Data2_port[5]), .D3(Data3_port[5]), .S0(Sel0), .S1(  
Sel1), .Y(Result[5]));  
MX4 MX4_Result_1_inst(.D0(Data0_port[1]), .D1(Data1_port[1]),  
.D2(Data2_port[1]), .D3(Data3_port[1]), .S0(Sel0), .S1(  
Sel1), .Y(Result[1]));  
MX4 MX4_Result_4_inst(.D0(Data0_port[4]), .D1(Data1_port[4]),  
.D2(Data2_port[4]), .D3(Data3_port[4]), .S0(Sel0), .S1(  
Sel1), .Y(Result[4]));  
MX4 MX4_Result_3_inst(.D0(Data0_port[3]), .D1(Data1_port[3]),  
.D2(Data2_port[3]), .D3(Data3_port[3]), .S0(Sel0), .S1(  
Sel1), .Y(Result[3]));
```

endmodule







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